DAQ Hardware

ISOTDAQ 2024
14th International School of Trigger and Data Acquisition
19-28 June 2024
University of Science and Technology of China (USTC), Hefei, China

Hefei, 19 Jun 2024

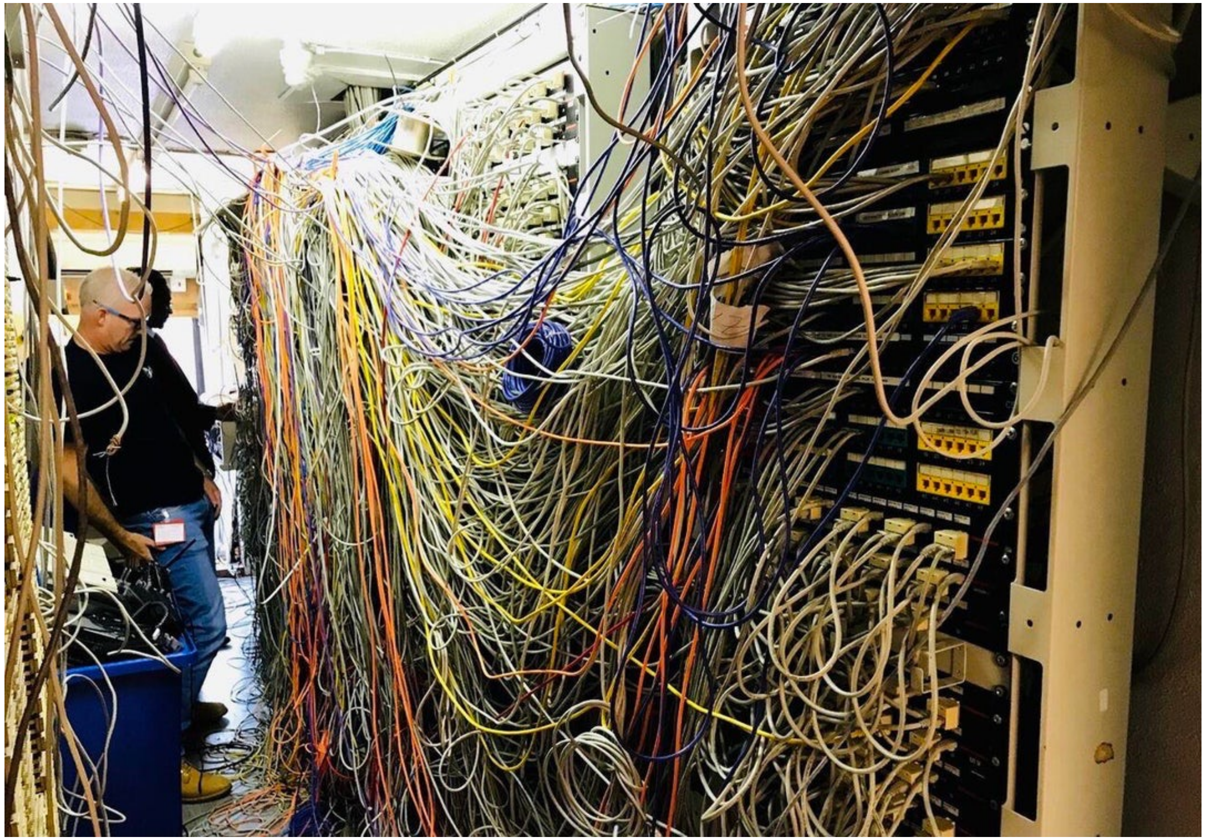
vincenzo.izzo@cern.ch

A Hands-on Approach

- This wants to be a hands-on approach to the basic DAQ hardware

A Hands-on Approach

- This wants to be a hands-on approach to the basic DAQ hardware



A Hands-on Approach

- This wants to be a hands-on approach to the basic DAQ hardware

Introduction

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will discuss quite simple different experiments, requiring different techniques and components
  - We also have some good real data to discuss
  - We'll see also issues you can encounter

Introduction

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will disc simple different experiments, req niques and components
  - e some good real data to discuss
  - e'll see also issues you can encounter

How does HW work?

Introduction

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will disc simple different experiments,
    req mponents
  - e some ge
  - We'll see also issues you can encounter

How does HW

Where do physics data come from?

Introduction

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will disc simple different experiments, req
  - ues you can encounter

does HW

Where d

How do physics events become bits and numbers?

Introduction

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will discuss quite simple different experiments, requiring different techniques and components
  - We also have some good real data to discuss
  - We'll see also issues you can encounter
- Acknowledgements
  - © Andrea Negri (Univ. of Pavia, Italy)
  - © Wainer Vandelli (CERN/PH-ATD)
  - © Sergio Ballestrero (Univ. Johannesburg & CERN)
    - Material and ideas have been taken from CERN Summer Student lectures of P.Farthouat, C.Joram and O.Ullaland; the "Physics data acquisition and analysis" lessons given by R.Ferrari at the University of Parma, Italy, "Analog and Digital Electronics for Detectors" of H. Spieler and all lectures of ISOTDAQ schools, in particular M.Joos and C.Schwick

Introduction on DAQ

From previous lecture (A. Negri)

- ➔"Data Acquisition" on Wikipedia: data acquisition (DAQ) is the process of **sampling signals** that measure real world physical conditions and **converting** the resulting samples into digital numeric values that....

- ➔Data acquisition is an **alchemy** of electronics, computer science, networking, physics

- …. resources and manpower matter as well, …

Introduction on DAQ

From previous lecture (A. Negri)

➔"Data Acquisition" on Wikipedia: data acquisition (DAQ) is the process of **sampling signals** that measure real world physical conditions and **converting** the resulting samples into digital numeric values that....

➔Data acquisition is an **alchemy** of electronics, computer science, networking, physics

- …. resources and manpower matter as well, …

➔DAQ is a wide and vast field, sometimes depending on the context

➔I will mostly refer to DAQ in High-Energy Physics experiments

Introduction on DAQ

From previous lecture (A. Negri)

➔"Data Acquisition" on Wikipedia: data acquisition (DAQ) is the process of **sampling signals** that measure real world physical conditions and **converting** the resulting samples into digital numeric values that....

➔Data acquisition is an **alchemy** of electronics, computer science, networking, physics

- …. resources and manpower matter as well, …

➔DAQ is a wide and vast field, sometimes depending on the context

- ➔I will mostly refer to DAQ in High-Energy Physics experiments
  - ➔We'll discuss only the basic principles of DAQ
    - ➔ Some of these might be the starting points for your next experiments

Electronics: What is needed for?

Typically, electronics interfaces DAQ with the detector

➔Collect electrical signals from the detector. Usually a short current pulse

Electronics: What is needed for?

Typically, electronics interfaces DAQ with the detector

➔Collect electrical signals from the detector. Usually a short current pulse.

Main roles:

1: Acquire & Shape the signal to optimize different, **incompatible**, characteristics
→ Compromise

- Detect minimum detectable signal
- Precise energy measurement
- Fast signal rate
- Precise timing
- Insensitivity to pulse shape

Electronics: What is needed for?

Typically, electronics interfaces DAQ with the detector

➔Collect electrical signals from the detector. Usually a short current pulse

Main roles:

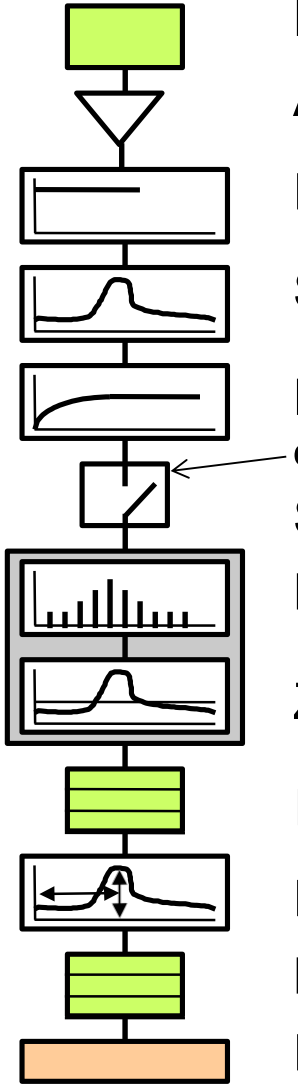
1: Acquire & Shape the signal to optimize different, **incompatible**, characteristics → Compromise

- Detect minimum detectable signal
- Precise energy measurement
- Fast signal rate
- Precise timing
- Insensitivity to pulse shape

2: Digitize the signal

- provide a digital representation of the measurement
- allow for subsequent processing, transmission, storage using digital electronics → Computers, Fibres, Networks, …

Readout chain



Detector

Amplifier

Filter

Shaper

Range compression

clock

Sampling

Digital filter

Zero suppression

Buffer

Feature extraction

Buffer

Format & Readout

➔Front-end electronics very specialized

- translates signals from a specific detector to a standard digital world
- custom build to match detector characteristics

➔We cannot discuss all design and architecture details

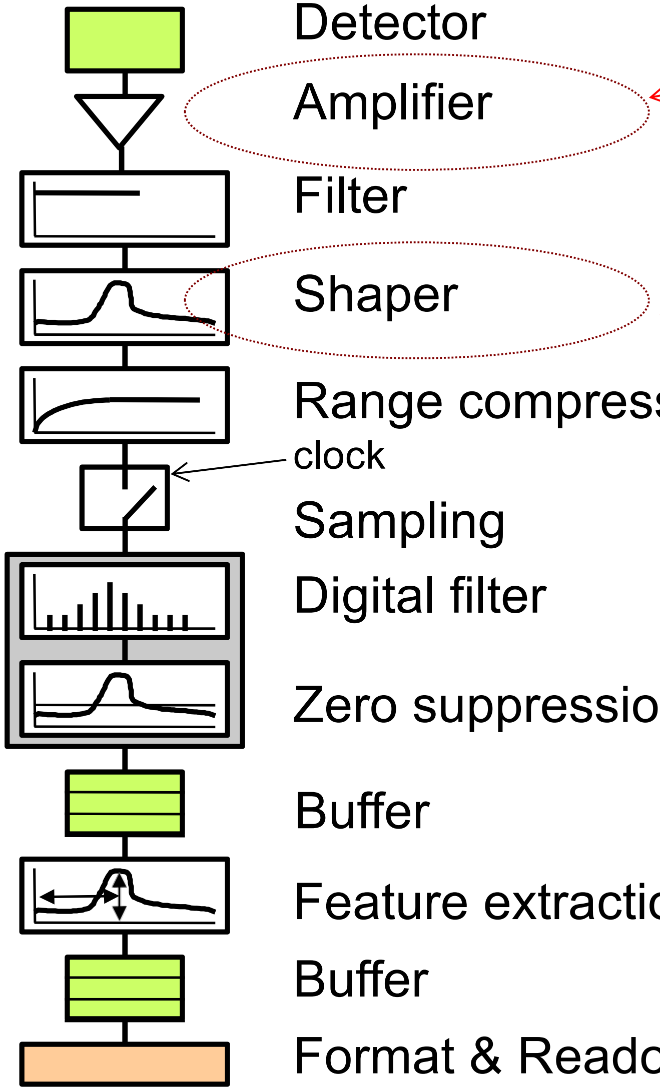
- if you are into electronic design you already know many topics

➔I want to provide you with basic guidelines

- This hopefully may help you when dealing or choosing commercial electronics
- If you need to design custom electronics, you need expertise in that field

➔We only discuss selected functions and principles

Readout chain



Detector

Amplifier

Filter

Shaper

Range compression

clock

Sampling

Digital filter

Zero suppression

Buffer

Feature extraction

Buffer

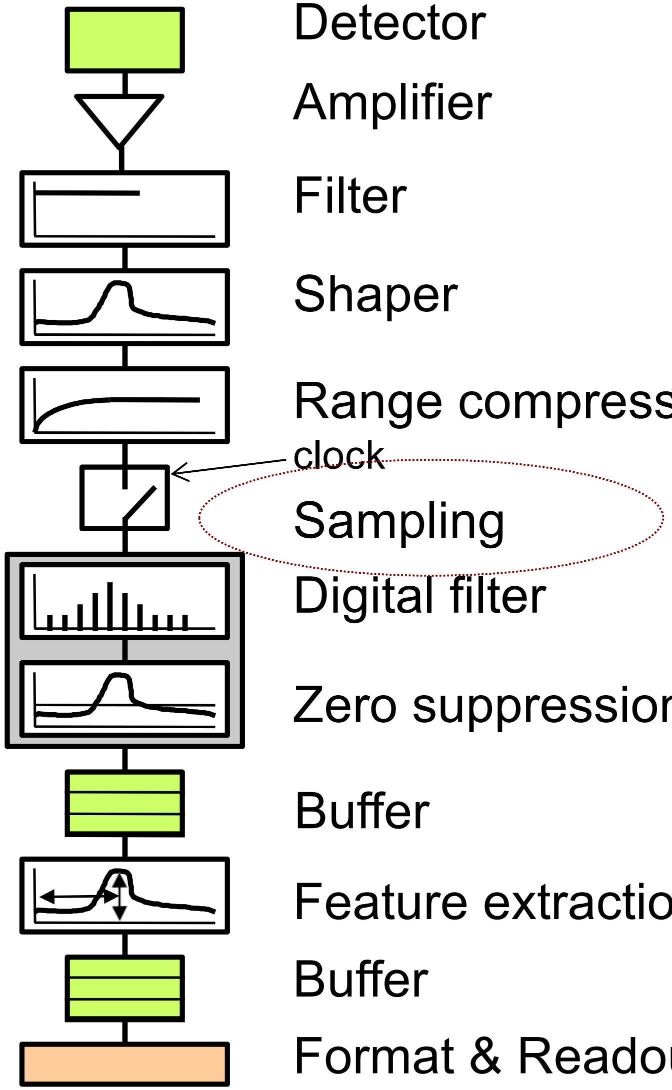
Format & Readout

Main functionalities:

- Amplify the tiny signal produced by the detector
- Improve Signal-to-Noise ratio

- Receive the (amplified) signal and give it a specific shape

Readout chain



Detector

Amplifier

Filter

Shaper

Range compression

clock

Sampling

Digital filter

Zero suppression

Buffer

Feature extraction

Buffer

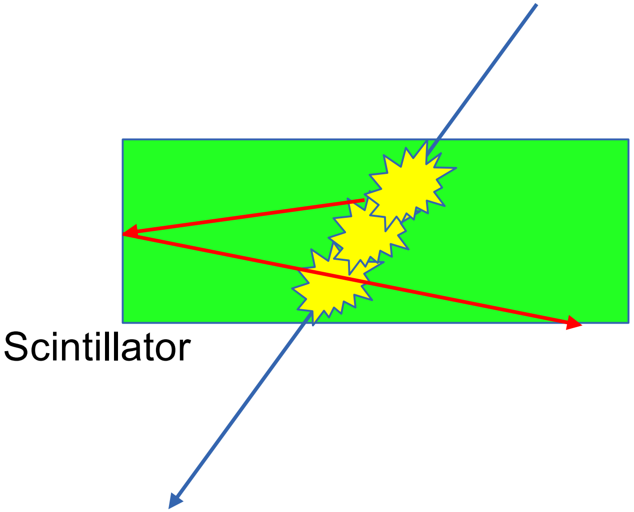
Format & Readout

Outline

- Introduction
  - DAQ, Electronics & Readout Chain
- Measure energy deposition
  - Scintillator setup
  - Photomultiplier
  - Analog-to-Digital conversion
  - Charge-to-Digital conversion
  - QDC in real life
- Measure position
  - Wire chamber setup
  - Time-to-Digital conversion
  - TDC in real life
- Corollary

You'll see in Labs 2-3

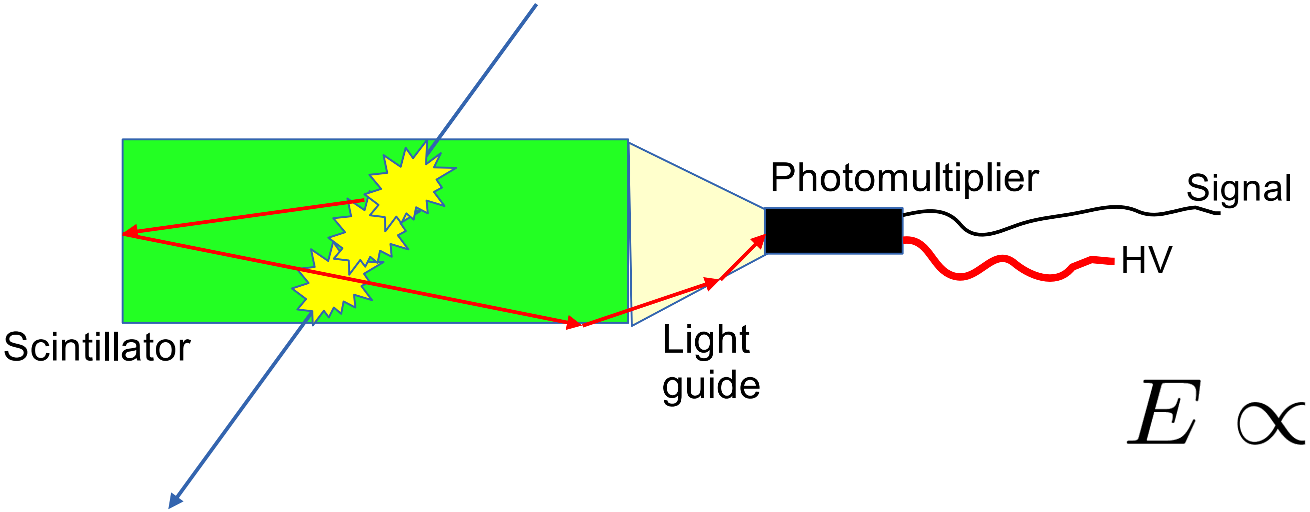
Energy measurement



$$E \propto N_\gamma$$

- Measure energy deposited by a particle traversing a medium
- The medium (detector) is a **scintillator**
  - Molecules, excited by the passing particle, relax emitting light
  - The amount of light is proportional to the deposited energy
  - We want to collect light with the highest possible collection efficiency

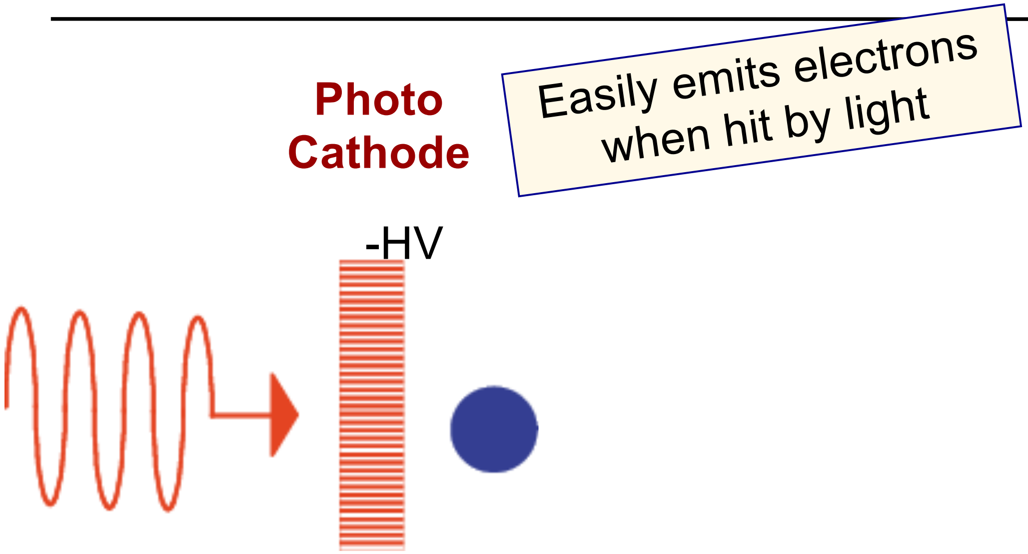
Energy measurement



$$E \propto N_\gamma$$

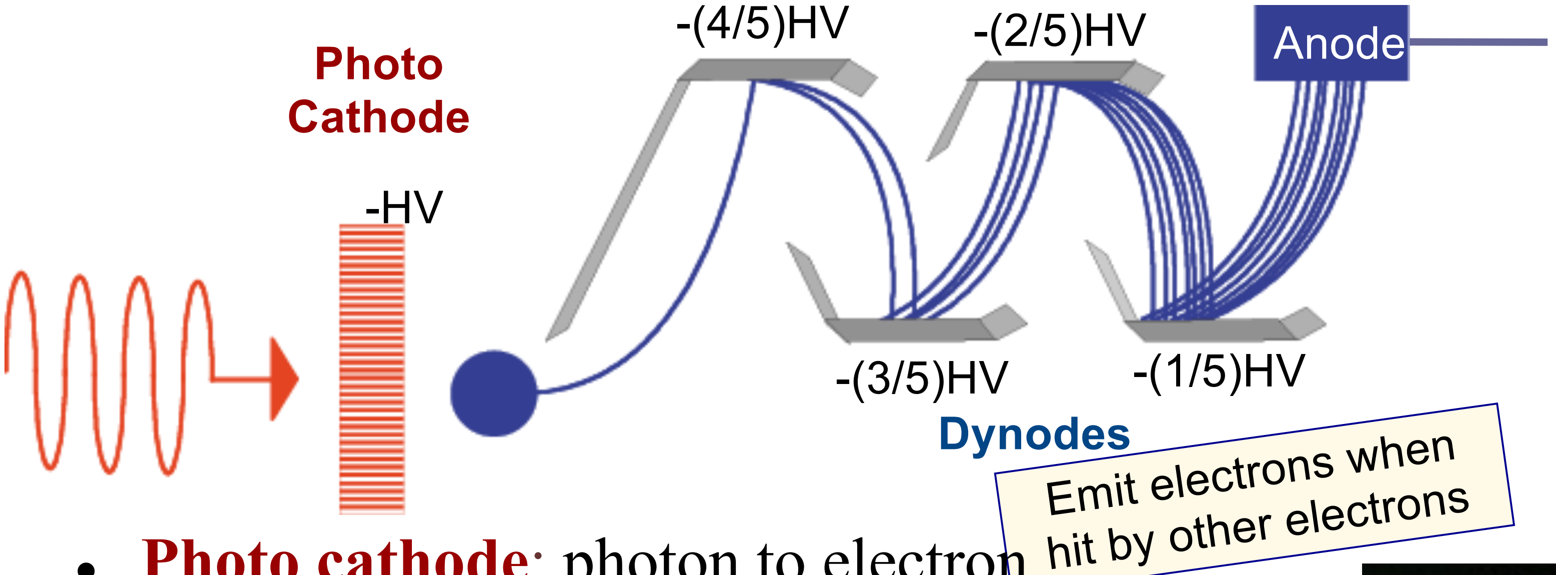
- Measure energy deposited by a particle traversing a medium
- The medium (detector) is a **scintillator**
  - Molecules, excited by the passing particle, relax emitting light
  - The amount of light is proportional to the deposited energy
  - We want to collect light with the highest possible collection efficiency
- The light is then
  - collected, using dedicated passive optical means (**light guide**)
  - fed into a photo-detector: **photomultiplier**

Photomultiplier



- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength

Photomultiplier

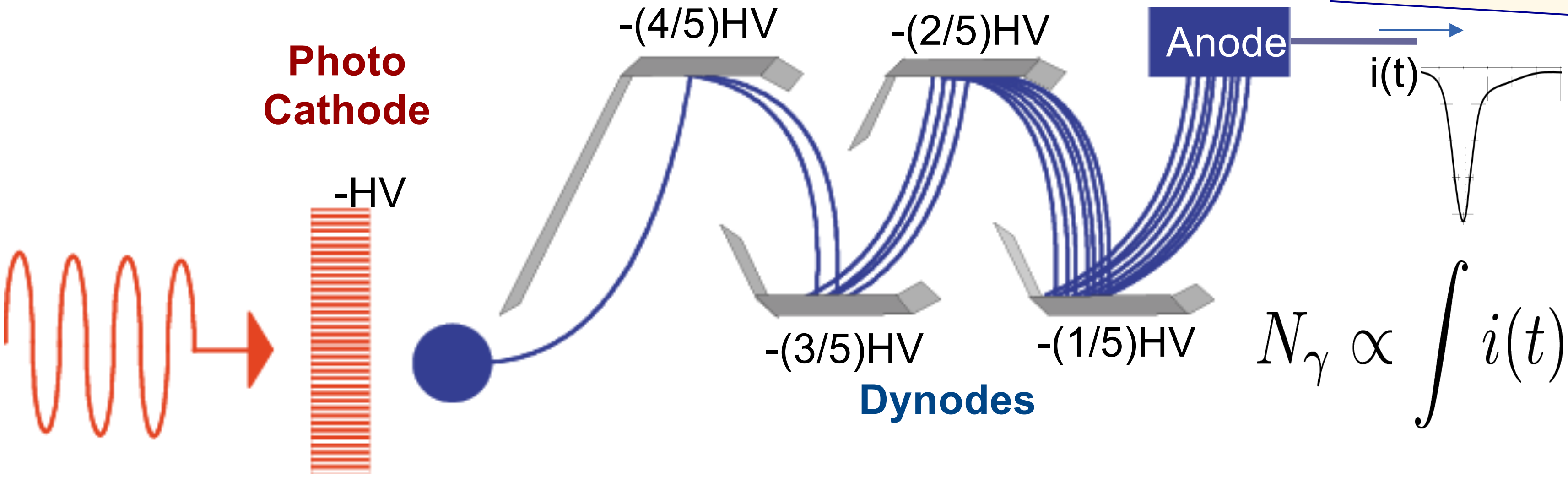


Emit electrons when hit by other electrons

- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength
- **Dynodes**: electrodes that amplify number of electrons thanks to secondary emission
  - Photocathode to anode: typical overall gain $\approx 10^6$

Photomultiplier

Very few photons converted into an electrical signal

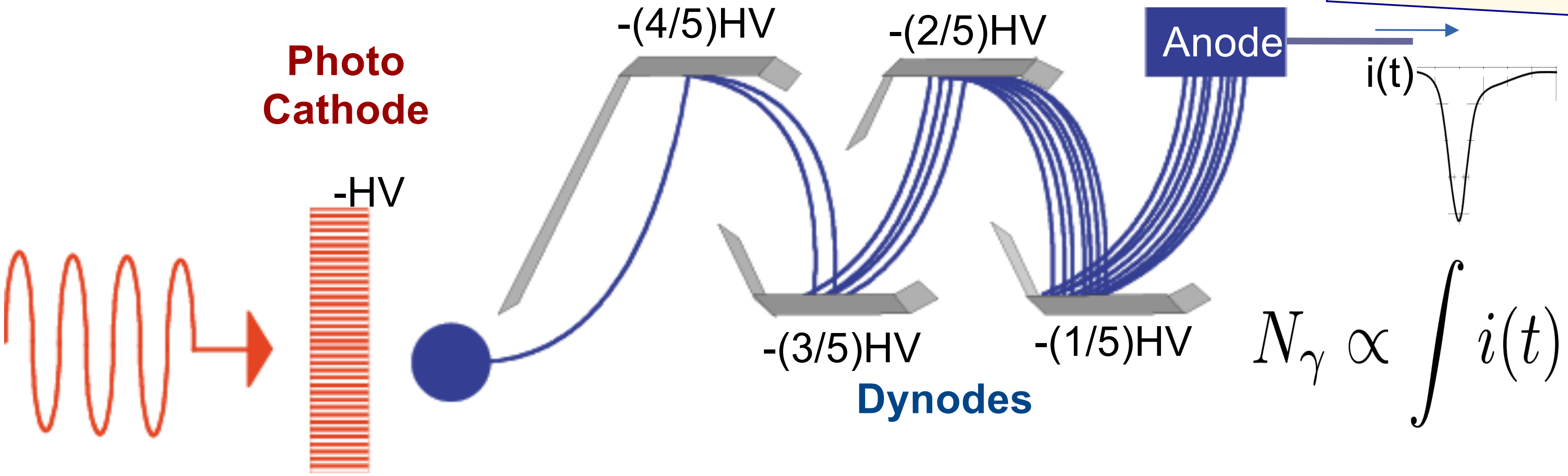


$$N_\gamma \propto \int i(t)\, dt = Q$$

- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength
- **Dynodes**: electrodes that amplify number of electrons thanks to secondary emission
  - Photocathode to anode: typical overall gain $\approx 10^6$

Photomultiplier

Very few photons converted into an electrical signal



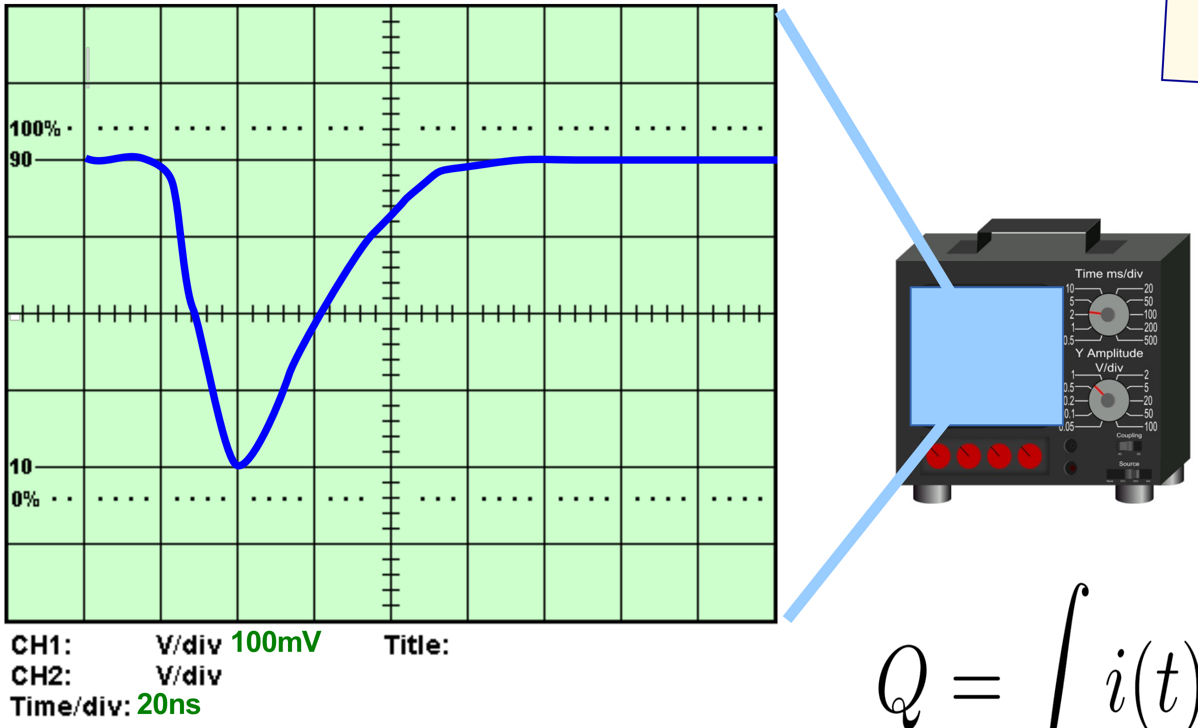
$$N_\gamma \propto \int i(t)\,dt = Q$$

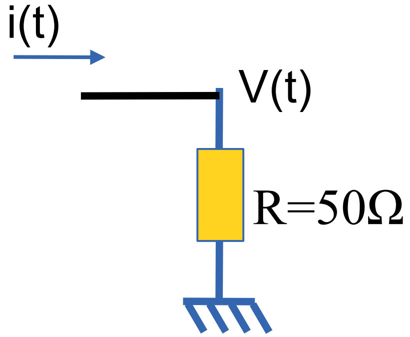
- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength
- **Dynodes**: electrodes that amplify number of electrons thanks to secondary emission
  - Photocathode to anode: typical overall gain $\approx 10^6$
- **Dark current**: noise
  - current flowing in PMT without light, due to thermal fluctuations

Start the measurement

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay

We start from an electron pulse, i.e. a current signal



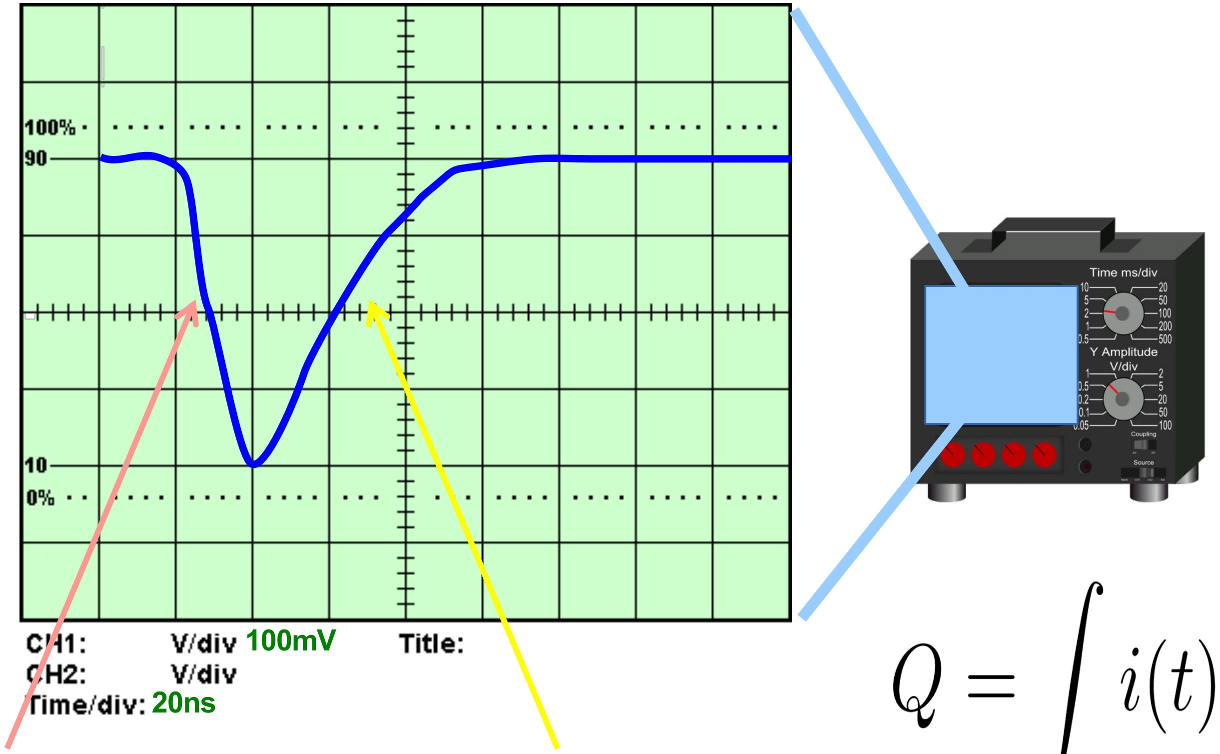


$$Q = \int i(t)\,dt = \frac{1}{R}\int V(t)\,dt$$

Remember: the TOTAL charge is proportional to the light

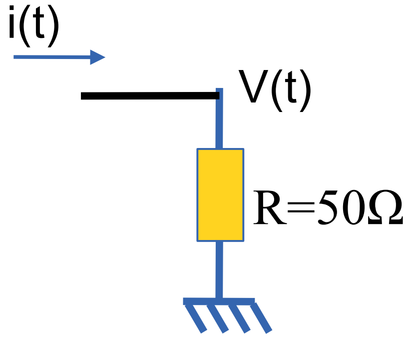
Start the measurement

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay



Fast rising edge

Exponential tail

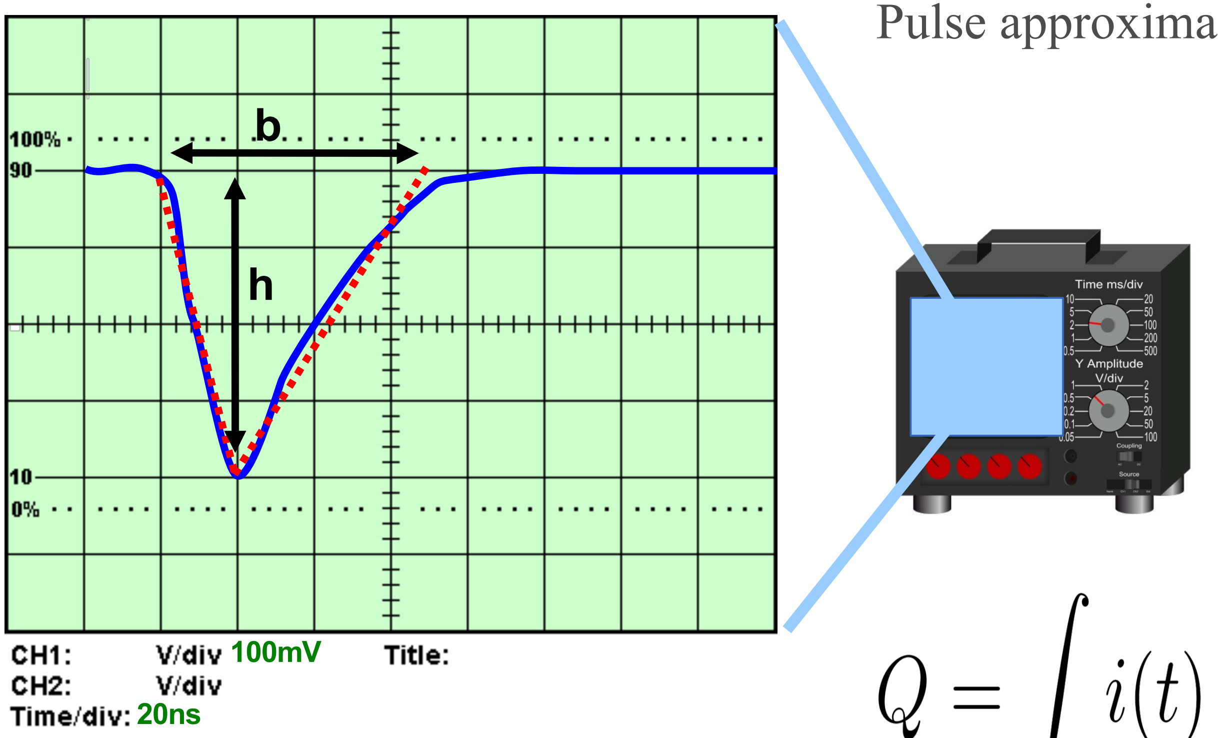


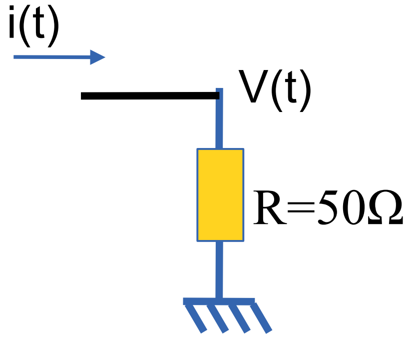
$$Q = \int i(t)\,dt = \frac{1}{R}\int V(t)\,dt$$

Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay:

Pulse approximates a triangle



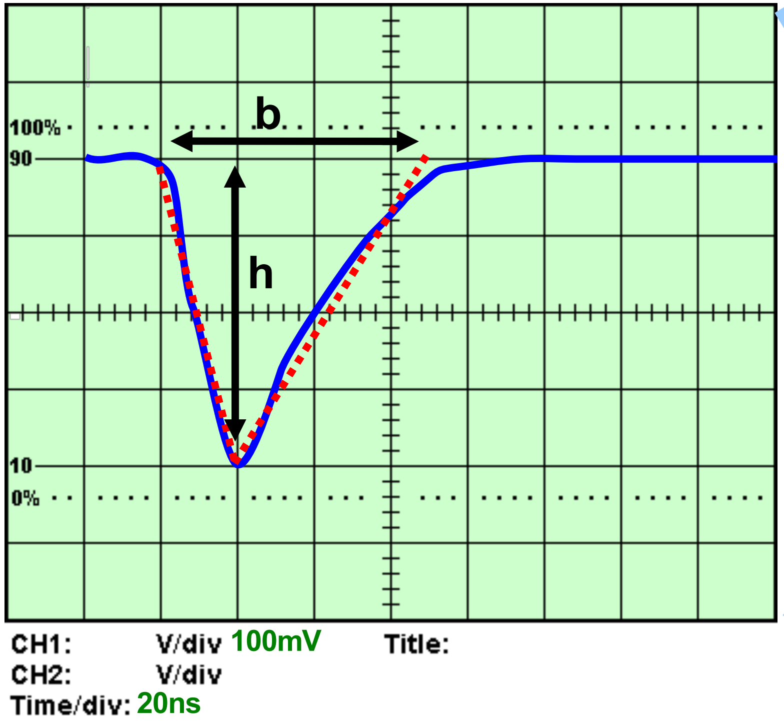


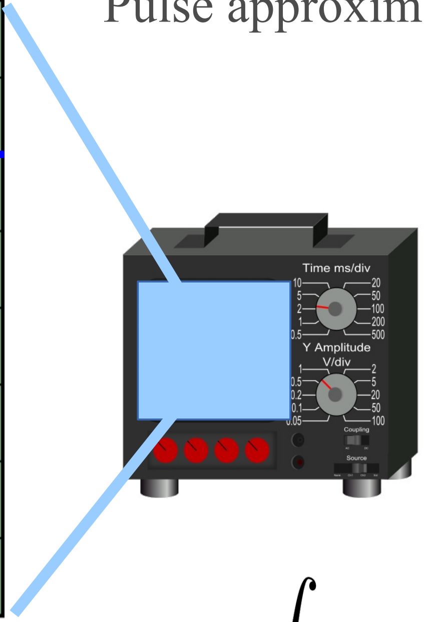
$$Q = \int i(t)\,dt = \frac{1}{R}\int V(t)\,dt$$

$$Q \approx \frac{1}{R}\frac{bh}{2} = \frac{1}{50\Omega}\frac{(3.5\cdot(20\text{ns}))(4\cdot(100\text{mV}))}{2} = 280\text{pC}$$

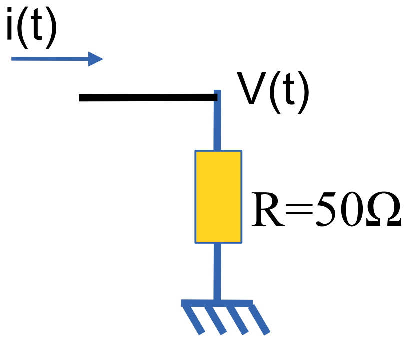
Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay





Pulse approximates a triangle



$$Q = \int i(t)\,dt = \frac{1}{R}\int V(t)\,dt$$

$$Q \approx \frac{1}{R}\frac{bh}{2} = \frac{1}{50\Omega}\frac{(3.5\cdot(20\text{ns}))(4\cdot(100\text{mV}))}{2} = 280\text{pC}$$

Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay
- We have a number representing our event!

Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay
- We have a number representing our event! It’s easy, but
  - Deadtime 3 – 5 min, ~ 3 × 10^{-3} Hz (if you are good)
  - Necessary to encode data into some sort of electronic format by hand, in order to manipulate it, visualize it, etc..

Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay
- We have a number representing our event! It’s easy, but
  - Deadtime 3 – 5 min, ~ 3×10^{-3} Hz (if you are good)
  - Necessary to encode data into some sort of electronic format by hand, in order to manipulate it, visualize it, etc.

LHC experiments have millions of channels to be acquired @40 MHz

Good old oscilloscope

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay
- We have a number representing our event! It’s easy, but
  - Deadtime 3 – 5 min, ~ 3 × 10^{-3} Hz (if you are good)
  - Necessary to encode data into some sort of electronic format by hand, in order to manipulate it, visualize it, etc.
- It would be much more convenient to have a direct electronic measurement
  - Save data in some digital format, fill a histogram on-line, etc ...

Good old oscilloscope

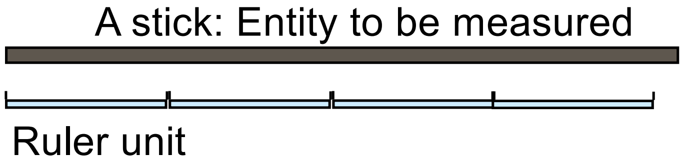
- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay
- We have a number representing our event! It’s easy, but
  - Deadtime 3 – 5 min, ~ 3 × 10^{-3} Hz (if you are good)
  - Necessary to encode data into some sort of electronic format by hand, in order to manipulate it, visualize it, etc.
- It would be much more convenient to have a direct electronic measurement
  - Save data in some digital format, fill a histogram on-line, etc ...
- N.B.: the oscilloscope method is still fundamental
  - it allows for the **validation** of your DAQ
  - yes, you should never thrust it a priori!

Analog to Digital Conversion

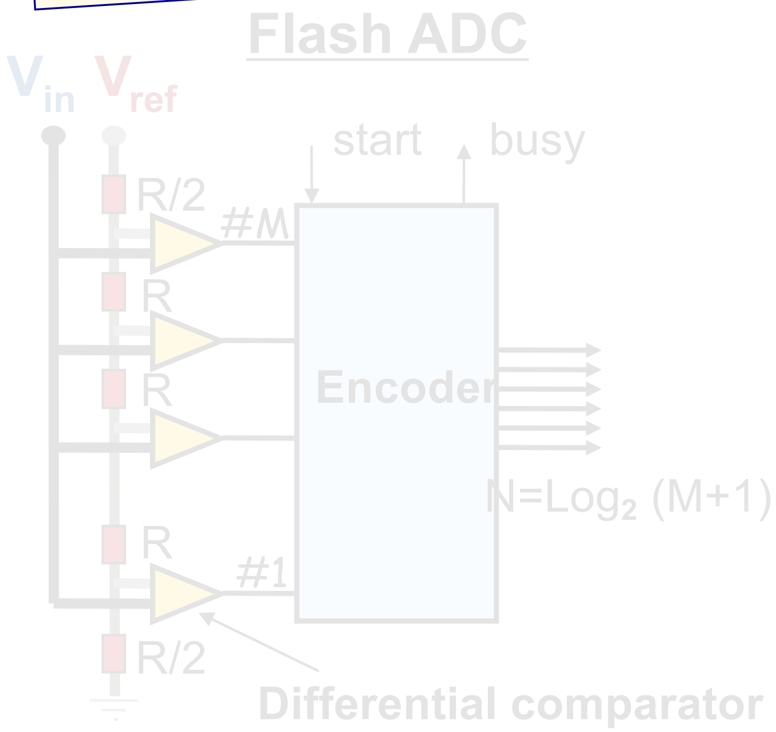
- Digitization

Lab 8

  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V_{in} compared with M fractions of a reference voltage
    - $(1/2)\ V_{ref}/M \rightarrow (M-1/2)\ V_{ref}\ /M$
    - E.g.: M=3
  - Result is encoded into a compact binary form of N bits
    - $N=\log_2 (M+1)$



We use this technique every day in our life

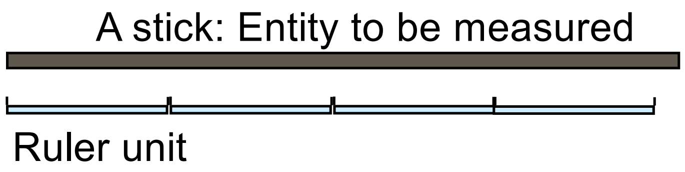


Analog to Digital Conversion

- Digitization

Lab 8

  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler

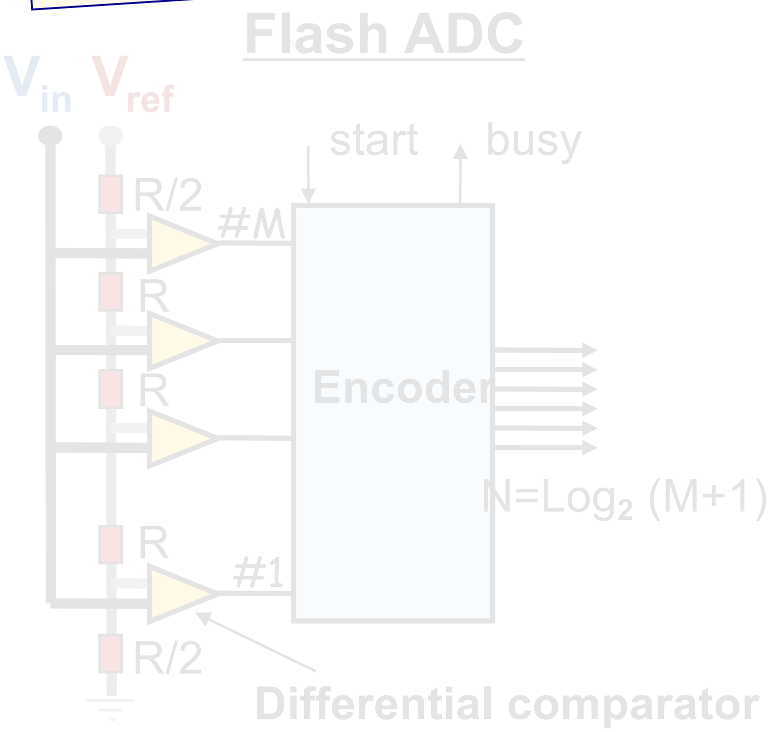


We use this technique every day in our life

- Flash ADC simplest and fastest implementation

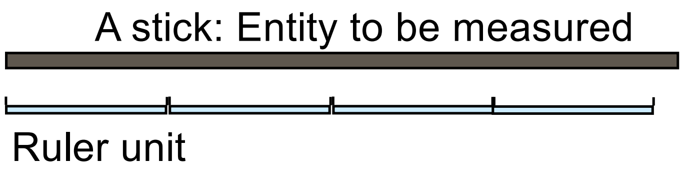
Now our entity is a voltage, and we need one (or more) voltage as a reference

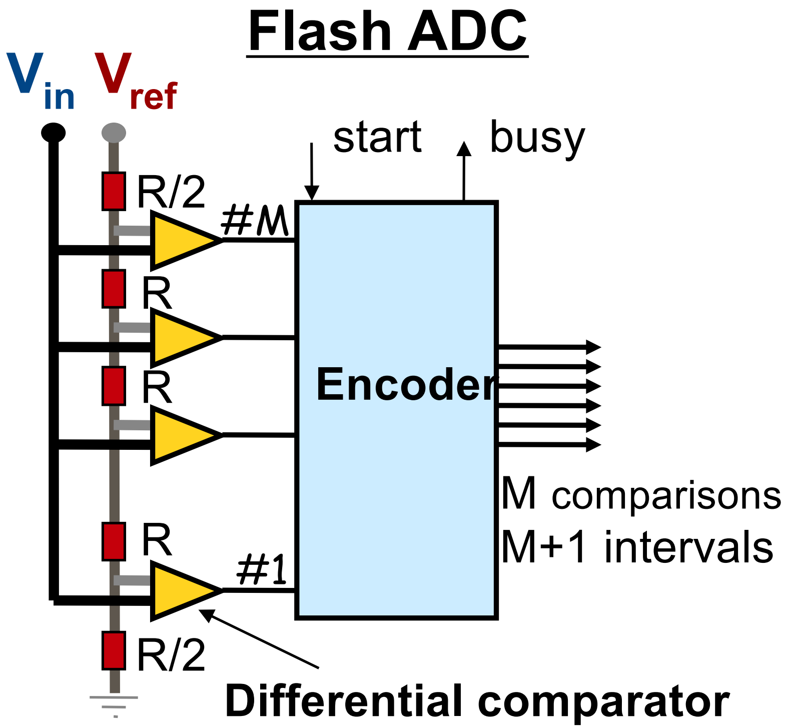
    - $(1/2)\ V_{ref}/M \rightarrow (M\text{-}1/2)\ V_{ref}/M$
    - E.g.: M=3
  - Result is encoded into a compact binary form of N bits
    - $N=\text{Log}_2\ (M+1)$



Analog to Digital Conversion

- Digitization
  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V_{in} compared with M fractions of a reference voltage
    - (1/2) V_{ref}/M → (M-1/2) V_{ref} /M
    - E.g.: M=3
  - Result is encoded into a compact binary form of N bits
    - $N=Log_2 (M+1)$



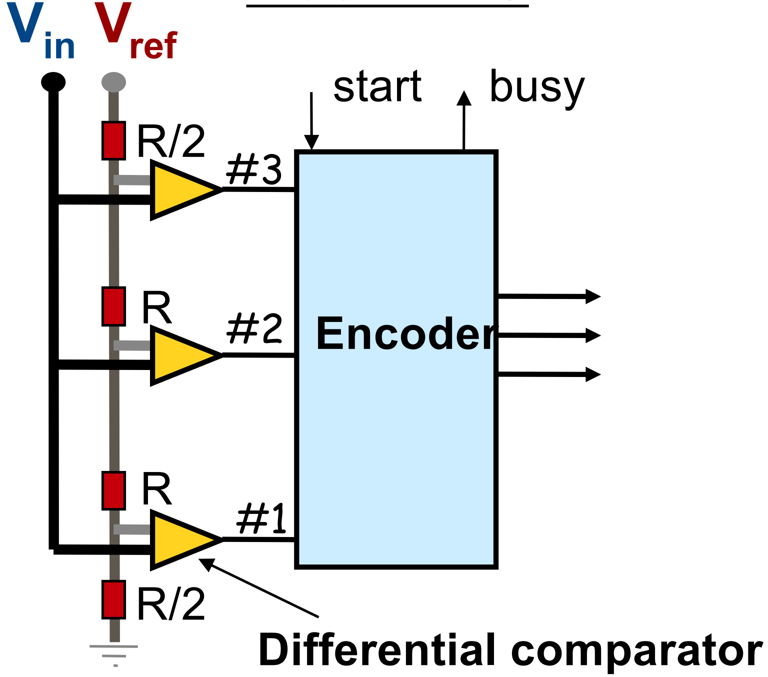


Analog to Digital Conversion

- Digitization
  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V_{in} compared with M fractions of a reference voltage
    - (1/2) V_{ref}/M → (M-1/2) V_{ref} /M
    - Example: M=3 comparisons
  - Result is encoded into a compact binary form of N bits
    - $N=\log_2(M+1)$

x = V_{in}/V_{ref}	Comparison results	Encoded form
x <1/6	000	00
1/6≤ x <3/6	001	01
3/6≤ x <5/6	011	10
5/6≤ x	111	11

Flash ADC

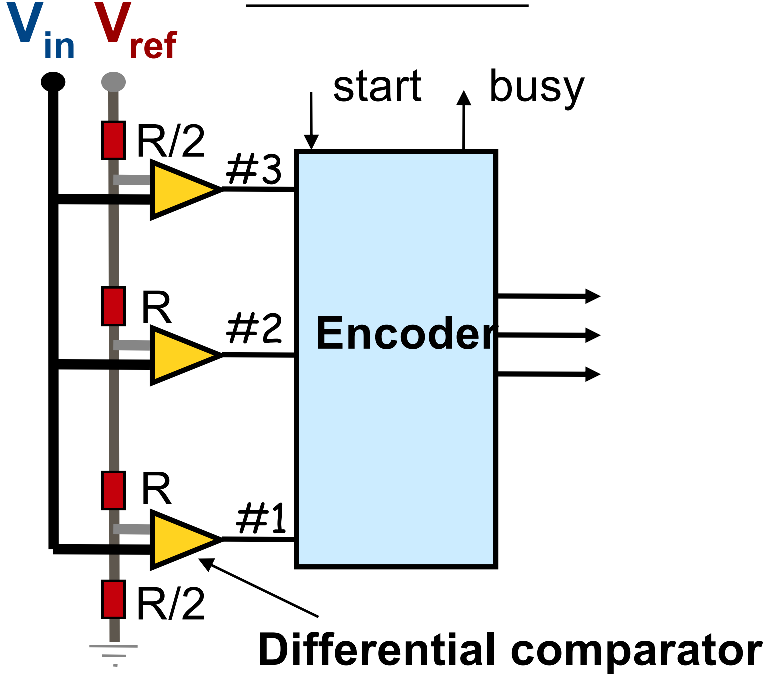


Analog to Digital Conversion

- Digitization
  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V_{in} compared with M fractions of a reference voltage
    - (1/2) V_{ref}/M → (M-1/2) V_{ref} /M
    - Example: M=3 comparisons
  - V_{in} / V_{ref} takes one of M+1 values.

x = V_{in}/V_{ref}	**Comparison results**	**Encoded form**
x <1/6	000	00
1/6≤ x <3/6	001	01
3/6≤ x <5/6	011	10
5/6≤ x	111	11

Flash ADC



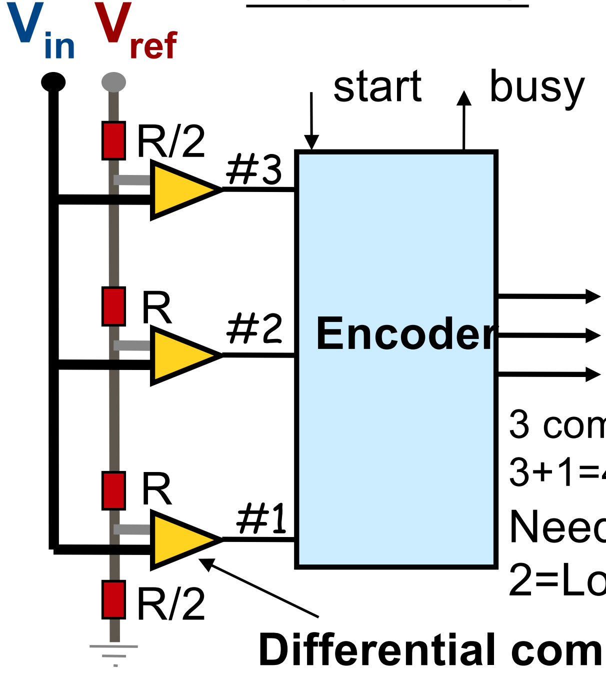
Analog to Digital Conversion

- Digitization
  - Encoding an analog value into a binary representation
  - By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V_{in} compared with M fractions of a reference voltage
    - (1/2) V_{ref}/M → (M-1/2) V_{ref} /M
    - Example: M=3 comparisons
  - V_{in} / V_{ref} takes one of M+1 values.

N-bit ADC { Result is encoded in compact binary form of N bits, $N=\text{Log}_2(M+1)$ bits

x = V_{in}/V_{ref}	Comparison results	Encoded form
x <1/6	000	00
1/6≤ x <3/6	001	01
3/6≤ x <5/6	011	10
5/6≤ x	111	11

Flash ADC



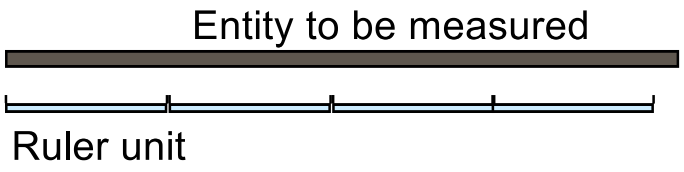
3 comparisons
3+1=4 values
Need 2 bits:
$2=\text{Log}_2(3+1)$

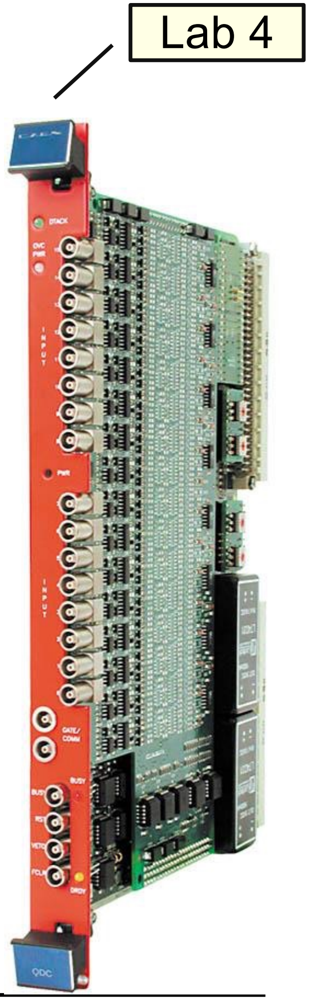
Differential comparator

ADC Characteristics

- We want to buy the ADC that best fits with our needs:

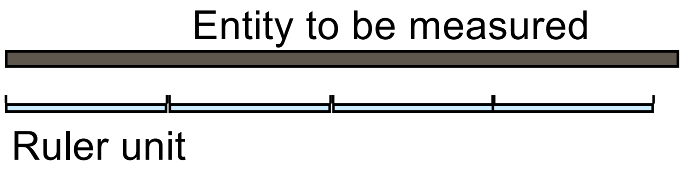
- Ideally, we want a very fast device, with very low power consumption, with less than 1 mV resolution, etc..



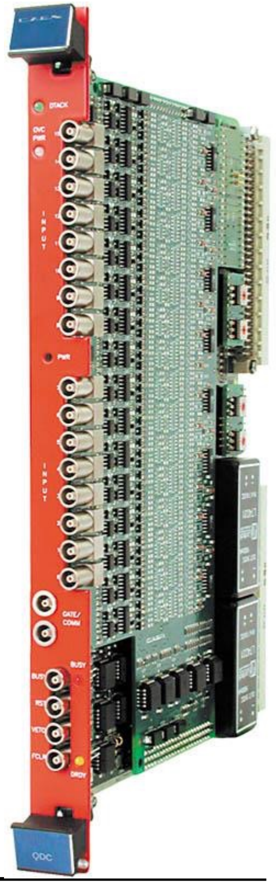


ADC Characteristics

- We want to buy the ADC that best fits with our needs:



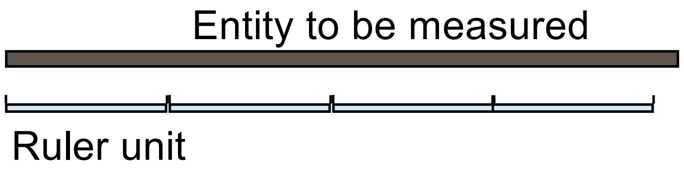
- Ideally, we want a very fast device, with very low power consumption, with less than 1 mV resolution, etc..



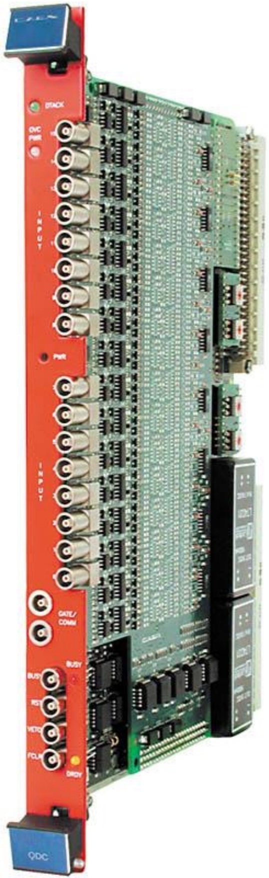
Lab 4

ADC Characteristics

- We want to buy the ADC that best fits with our needs:



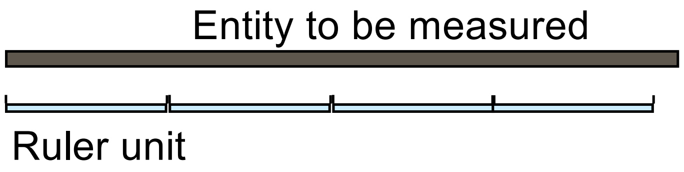
- Ideally, we want a very fast device, with very low power consumption, with less than 1 mV resolution, etc..

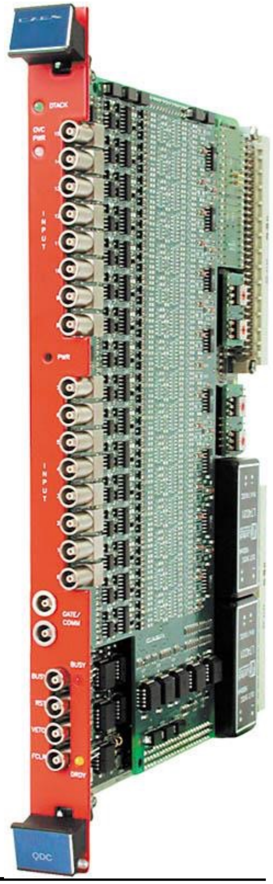


Lab 4

ADC Characteristics

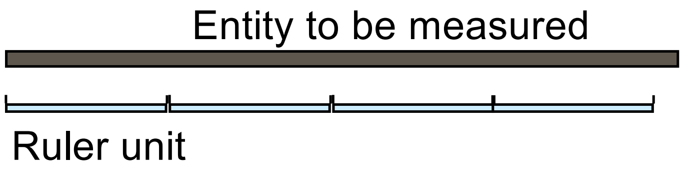
- Resolution (LSB), the ruler unit: $V_{max}/2^N$
  - e.g.: 1V and 8bit (M=256) → LSB = 3.9 mV
  - e.g.: 1V and 10bit (M=1024) → LSB = 0.97 mV



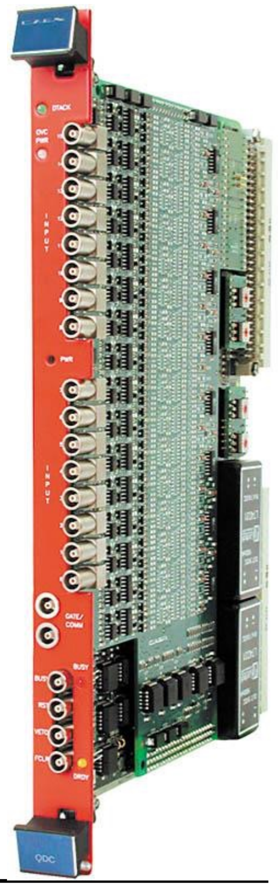

Lab 4

ADC Characteristics

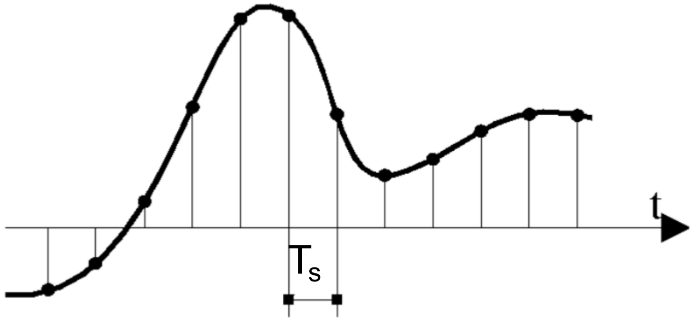
- Resolution (LSB), the ruler unit: $V_{max}/2^N$
  - e.g.: 1V and 8bit (M=256) → LSB = 3.9 mV
  - e.g.: 1V and 10bit (M=1024) → LSB = 0.97 mV
- Quantization error: ±LSB/2



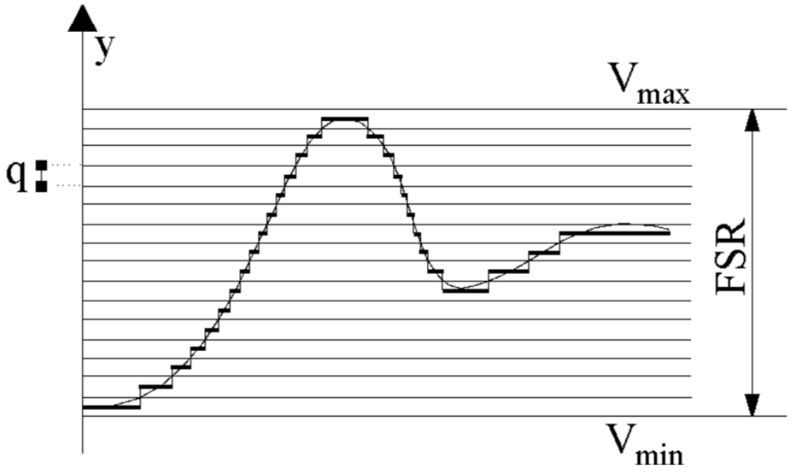
Lab 4



Sampled signal, S(t)



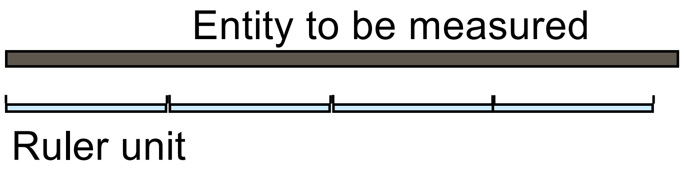
Sampling frequency, $f_s=1/T_s$



Amplitude coding with N=4
(16 different steps)

ADC Characteristics

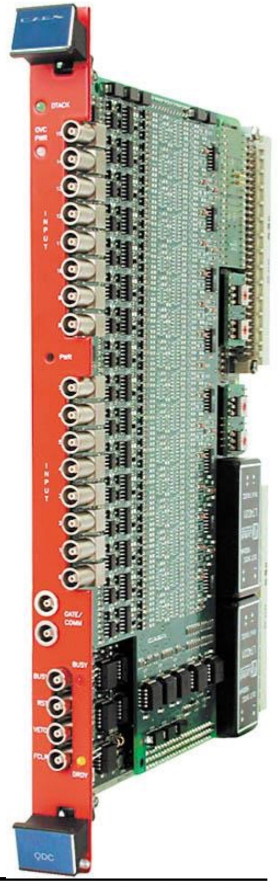
- Resolution (LSB), the ruler unit: $V_{max}/2^N$
  - e.g.: 1V and 8bit (M=256) → LSB = 3.9 mV
  - e.g.: 1V and 10bit (M=1024) → LSB = 0.97 mV



- Quantization error: ±LSB/2

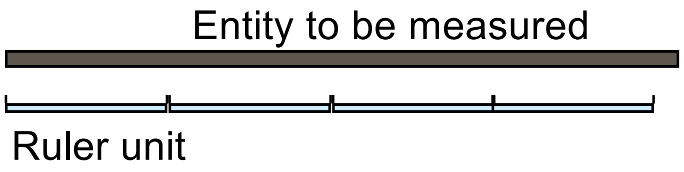
Resolution depends on the number of comparators in the ADC

The N (number of bits) essentially tells you how many steps you have in the ADC

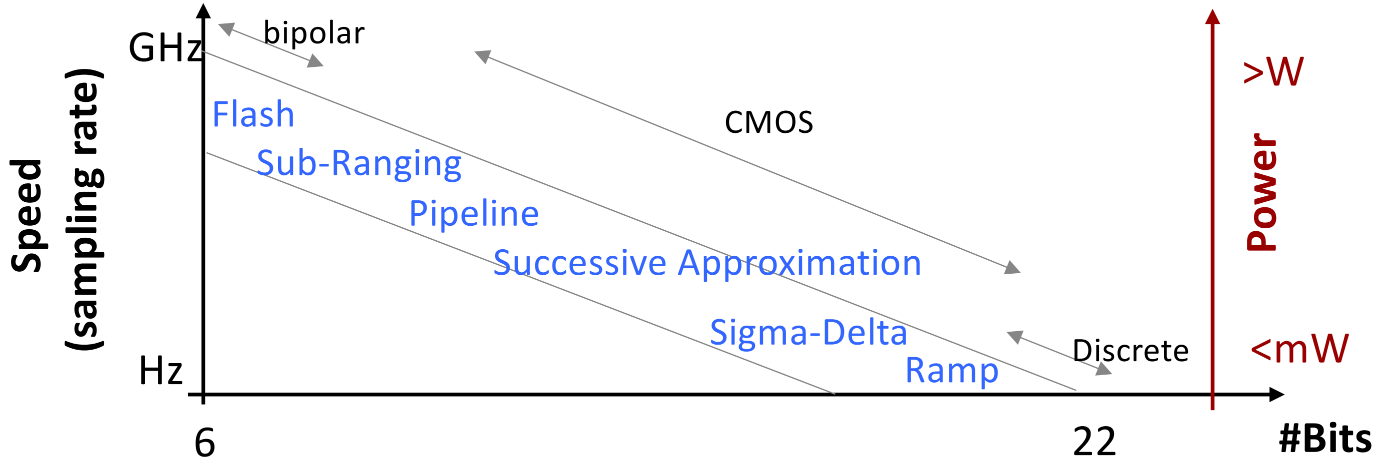

Lab 4

ADC Characteristics

- Resolution (LSB), the ruler unit: $V_{max}/2^N$
  - e.g.: 1V and 8bit (M=256) → LSB = 3.9 mV
  - e.g.: 1V and 10bit (M=1024) → LSB = 0.97 mV

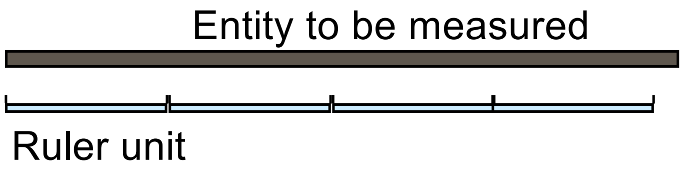


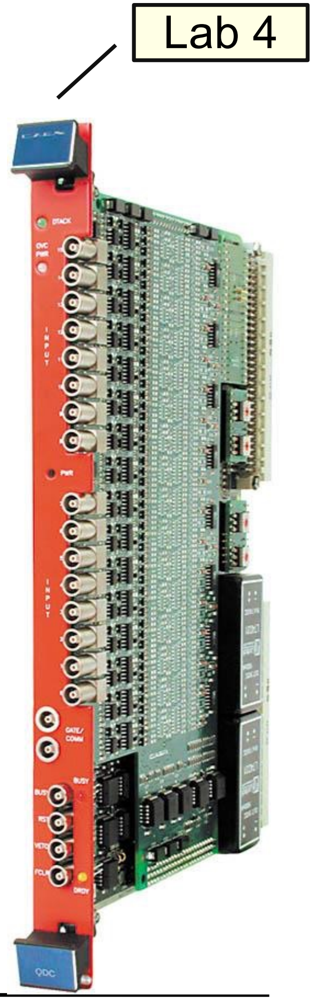
- Quantization error: ±LSB/2
- Accuracy: see next slide
- Many different ADC architecture/technique exists
  - mostly because of the trade-off between speed and resolution



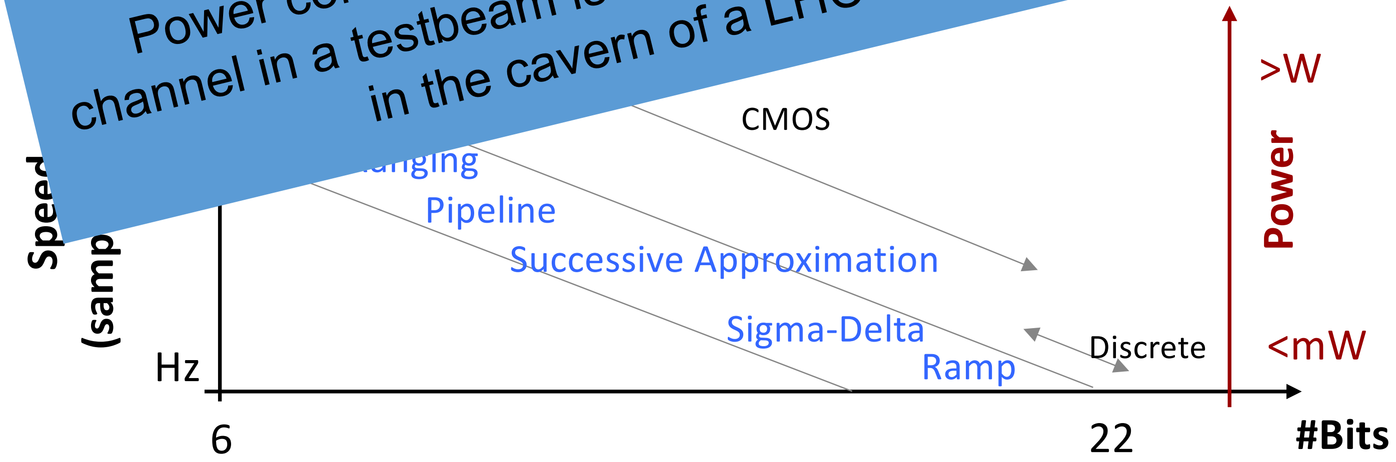
ADC Characteristics

- Resolution (LSB), the ruler unit: $V_{max}/2^N$
  - e.g.: 1V and 8bit (M=256) → LSB = 3.9 mV
  - e.g.: 1V and 10bit (M=1024) → LSB = 0.97 mV
- Quantization error: ±LSB/2
- Accuracy: see next slide
- Many different ADC
  - most olution



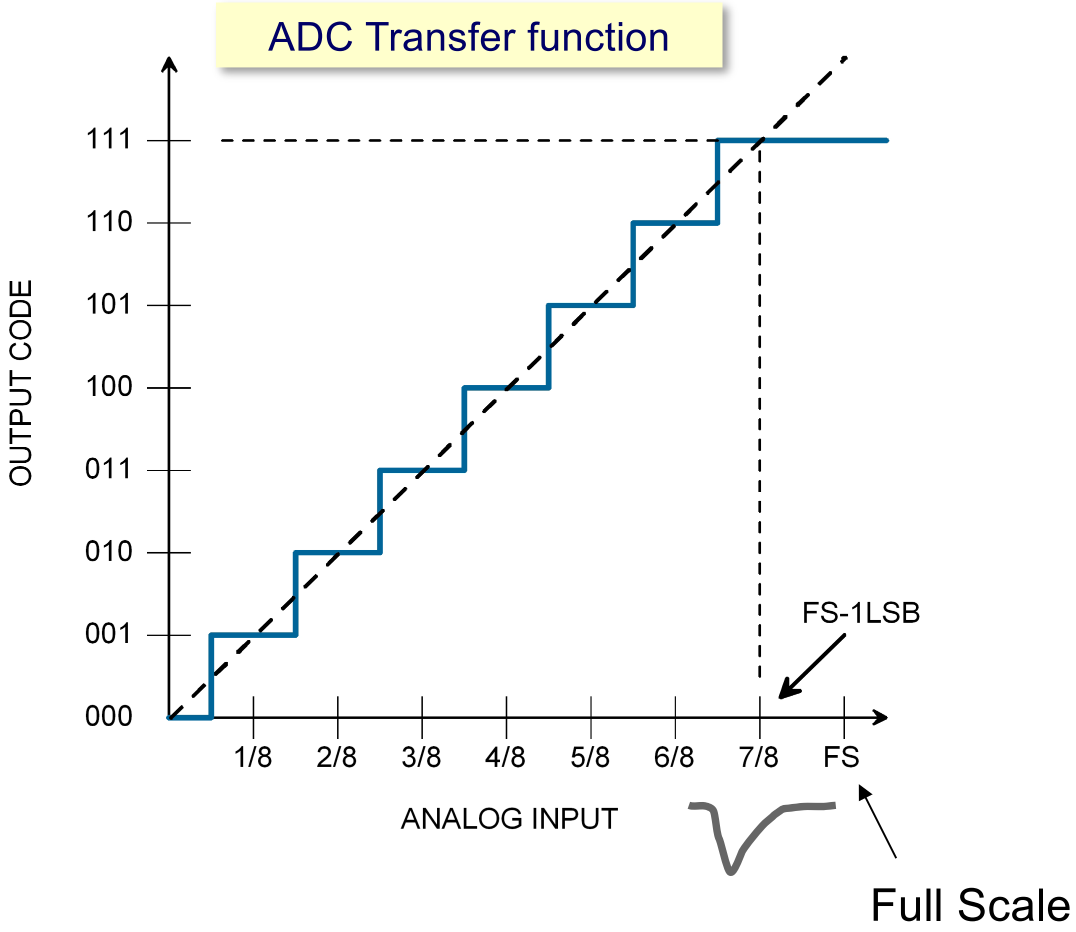


Power consumption also matters sometimes: 1 W per channel in a testbeam is very different from 1 W per channel in the cavern of a LHC experiment



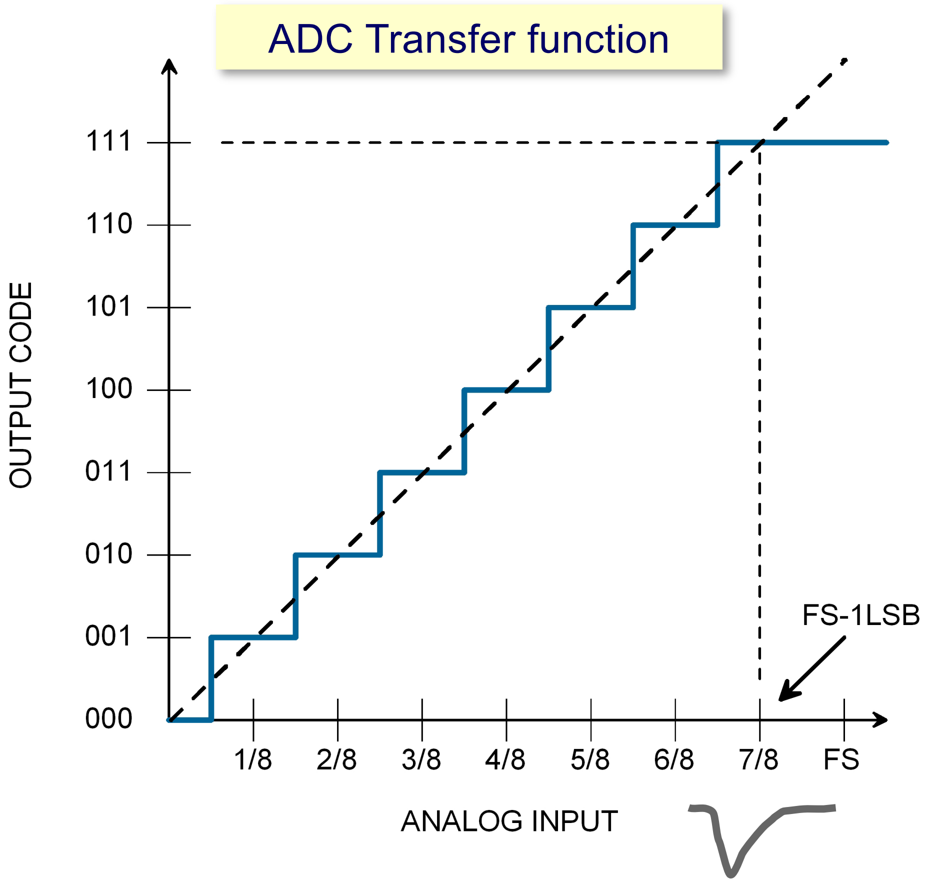
ADC Accuracies

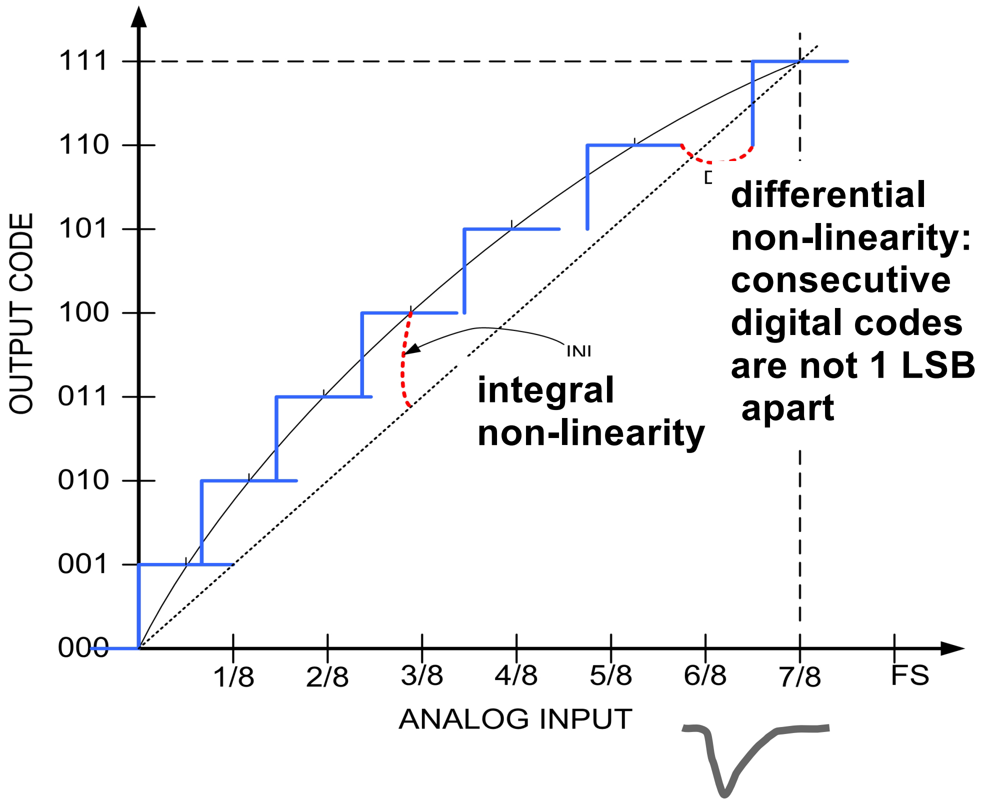
- ADC transfer function
  - Output code vs analog input



ADC (In)Accuracies

- ADC transfer function
  - Output code vs analog input


ADC Transfer function



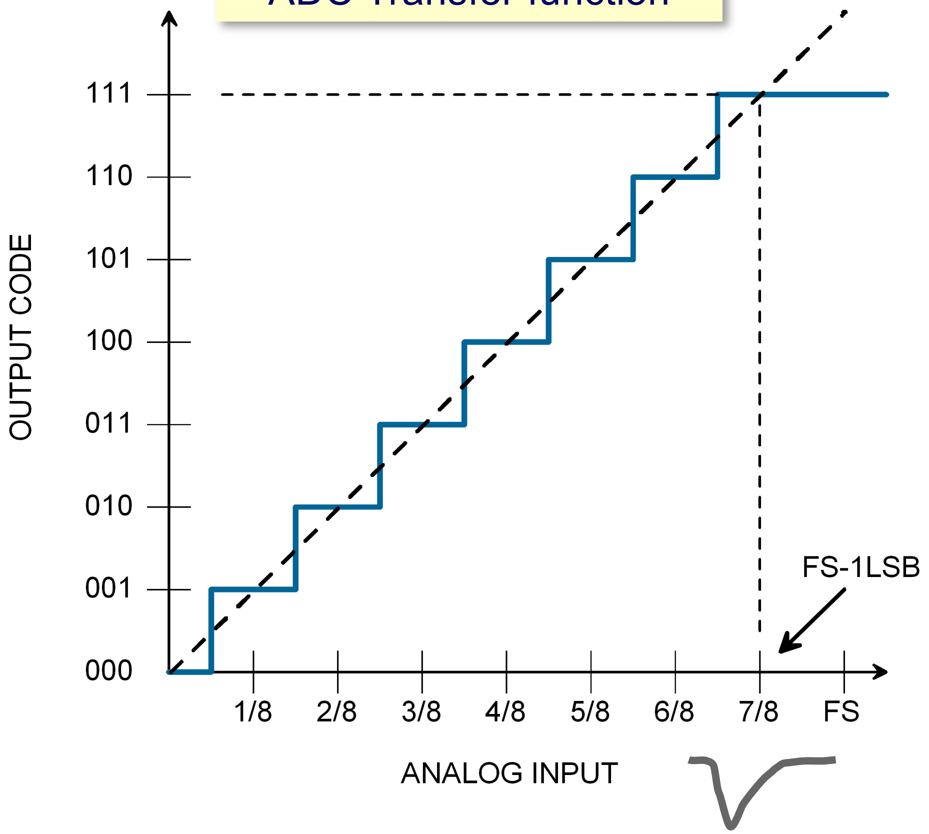
integral non-linearity

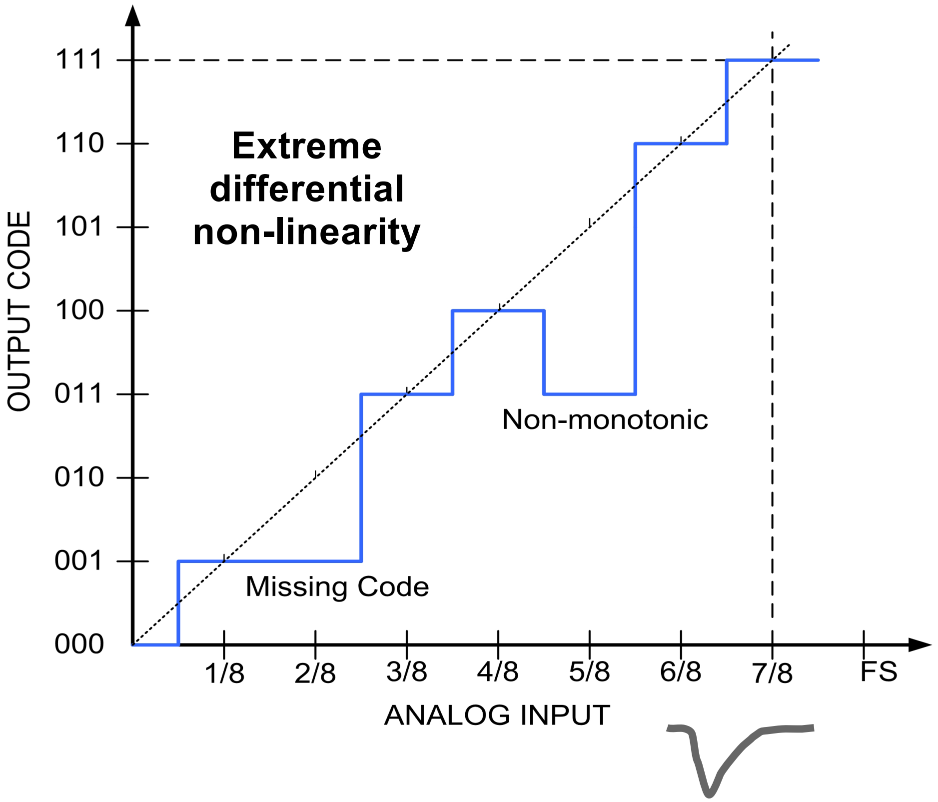
differential non-linearity: consecutive digital codes are not 1 LSB apart

ADC (In)Accuracies

- ADC transfer function
  - Output code vs analog input

ADC Transfer function

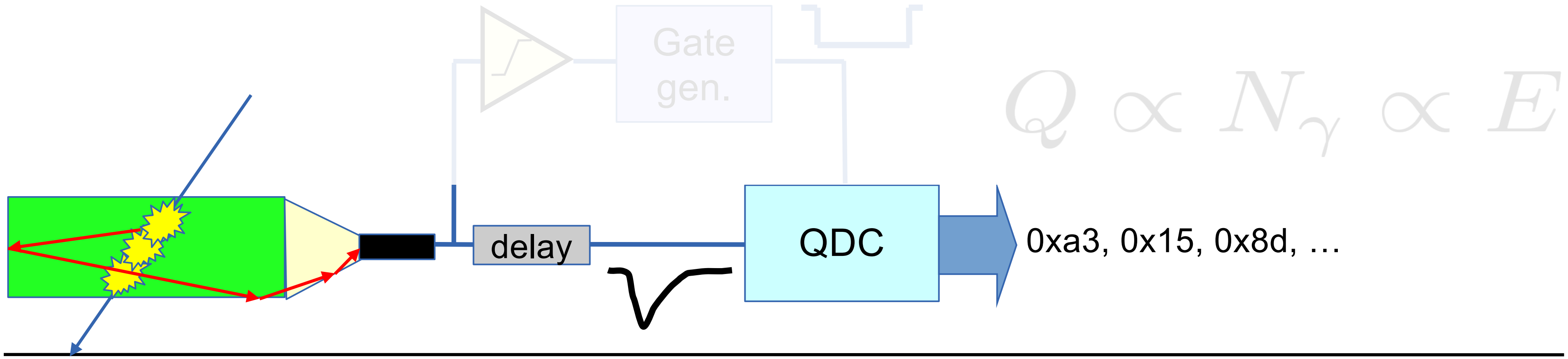




Charge to Digital

- ADC converts a voltage into a digital representation
  - However, in our experiment, we have a current and we are interested in the total charge
- We need a QDC (Charge to Digital Converter)
  - Essentially an integration step followed by an ADC
  - Integration requires limits → gate

$$I = \int_a^b f(x)\, dx$$

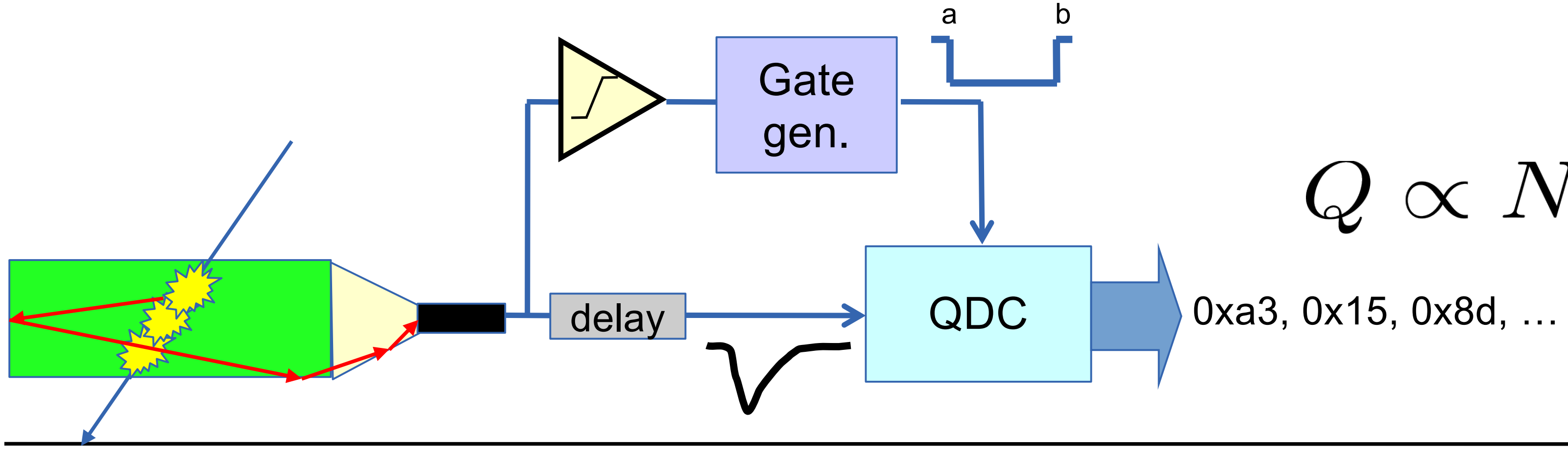


$$Q \propto N_\gamma \propto E$$

Charge to Digital

- ADC converts a voltage into a digital representation
  - However, in our experiment, we have a current and we are interested in the total charge
- We need a QDC (Charge to Digital Converter)
  - Essentially an integration step followed by an ADC
  - Integration requires limits → gate

$$I = \int_a^b f(x)\,dx$$



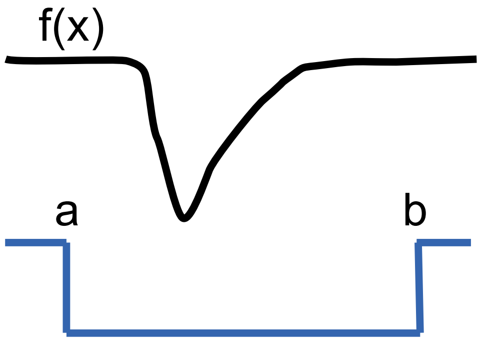
$$Q \propto N_\gamma \propto E$$

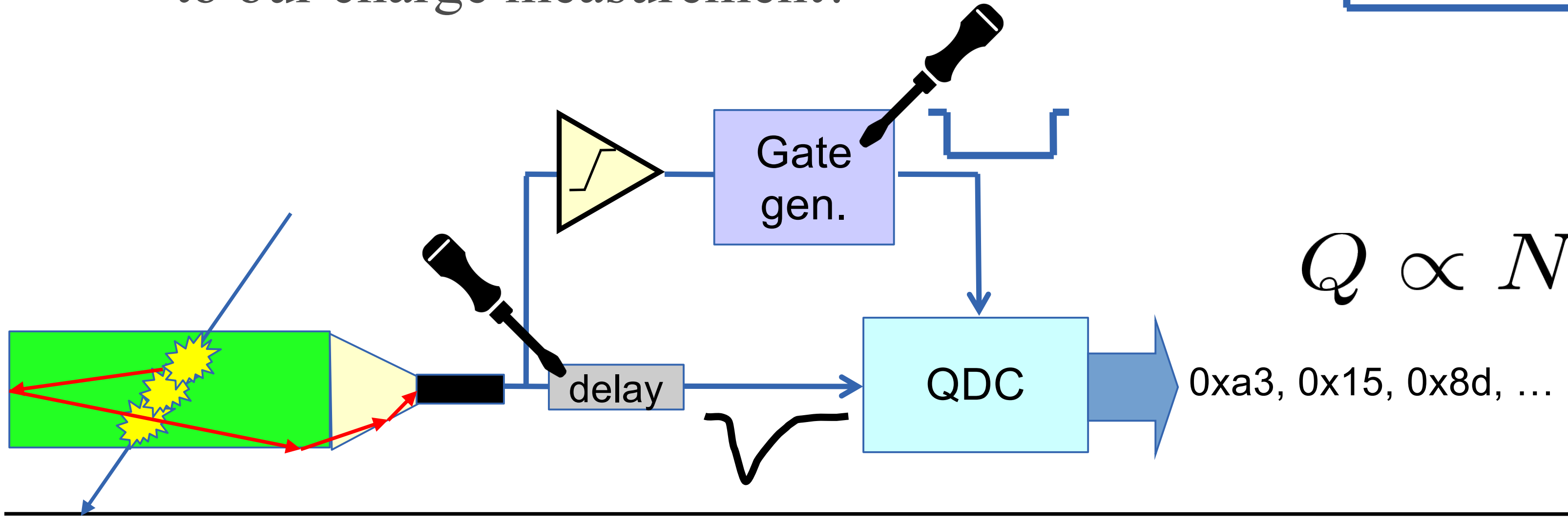
QDC: timing

- Relative timing between <u>signal</u> and <u>gate</u> is important
  - Delay tuning

Labs 2, 3, 4

- Gate should be **large enough** to contain the full pulse and to accommodate for the jitter
  - Fluctuations are always with us!
- Gate should **not** be **too large**
  - Increases the noise level
  - By the way, which is the noise contribution to our charge measurement?

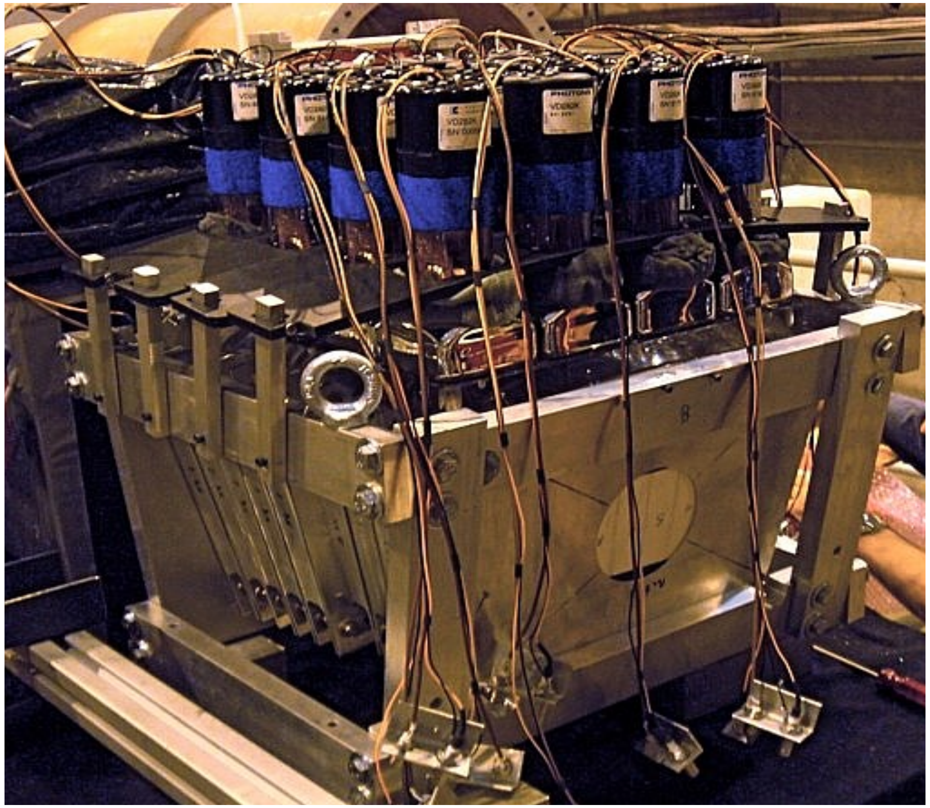


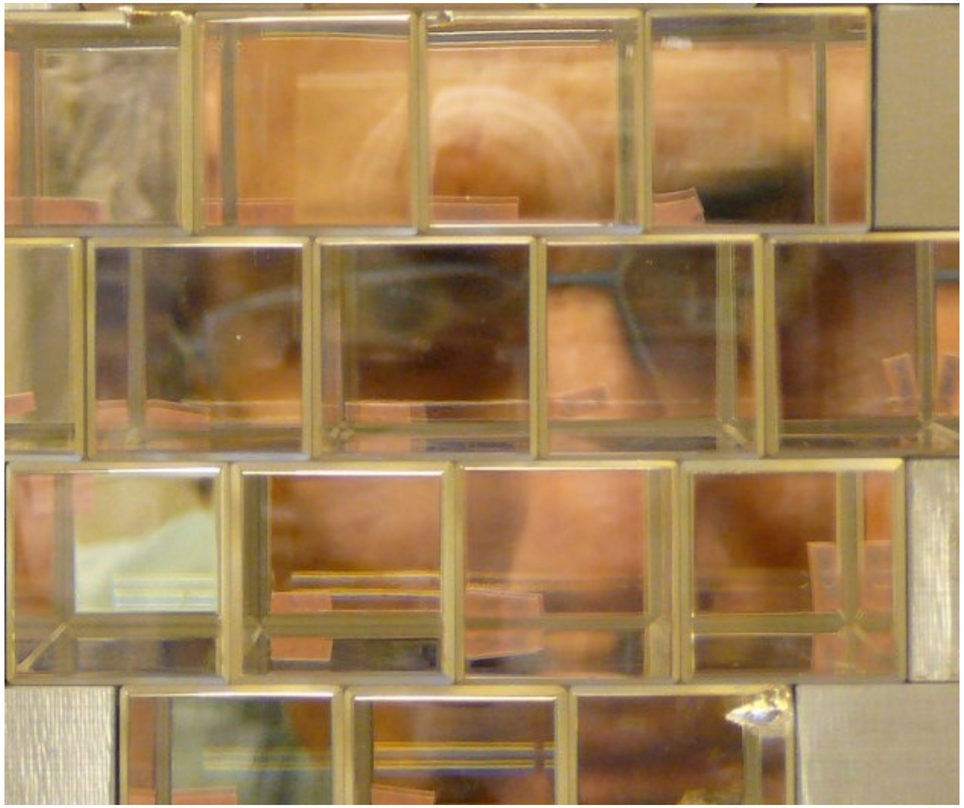


$$Q \propto N_\gamma \propto E$$

Example of QDC data

- Calorimetry R&D test beam @CERN
  - QDC spectra $Q \propto N_\gamma \propto E$



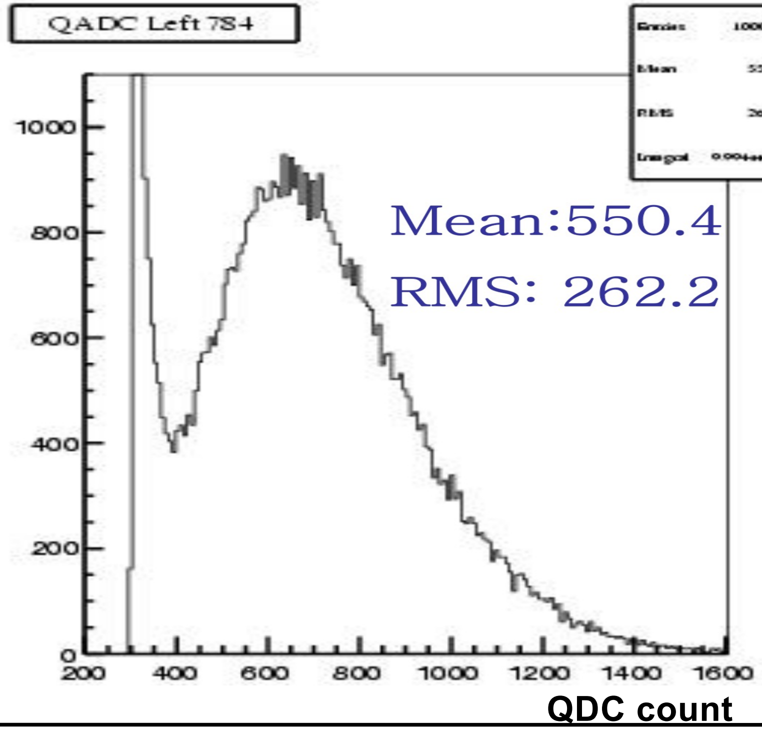


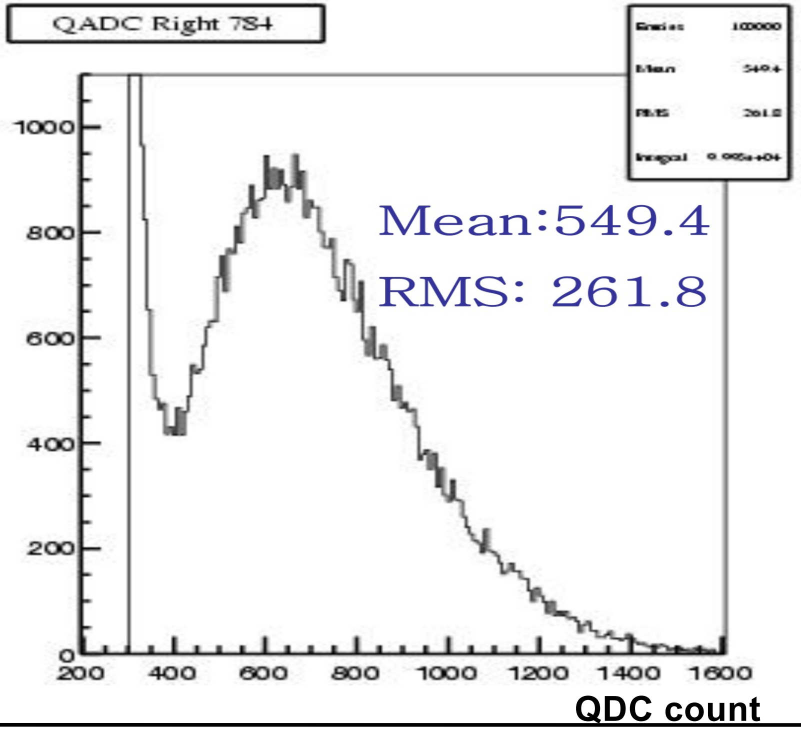
QDC spectra

- Calorimetry R&D test beam @CERN
  - QDC spectra

$$Q \propto N_\gamma \propto E$$

- But, what is the 1st peak?
  - How can we estimate it?



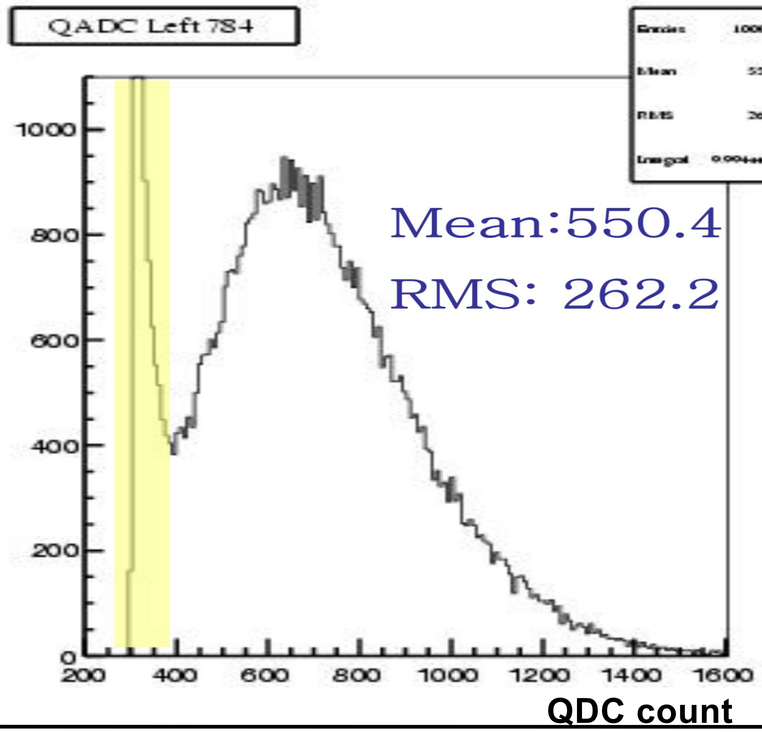


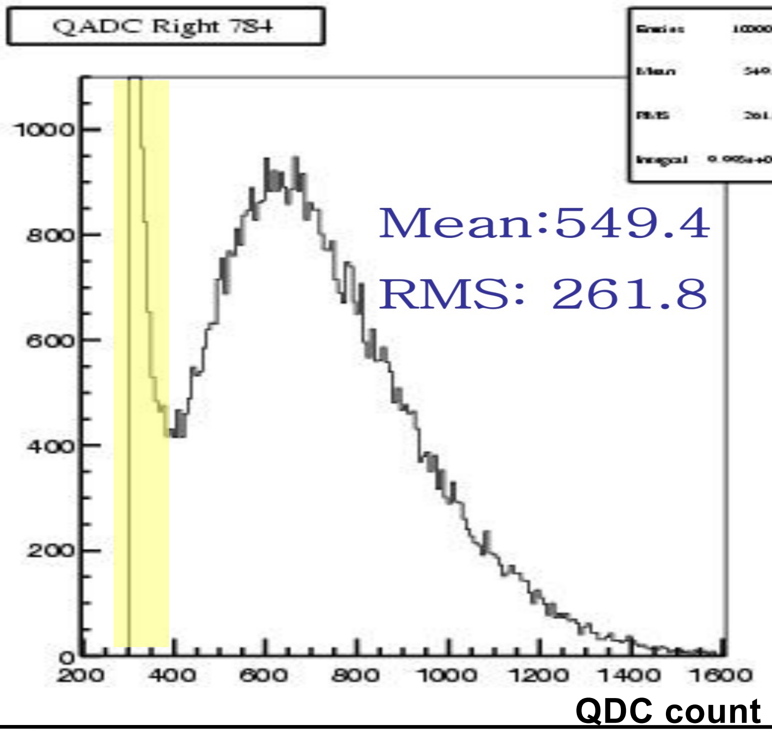
QDC spectra

- Calorimetry R&D test beam @CERN
  - QDC spectra

$$Q \propto N_\gamma \propto E$$

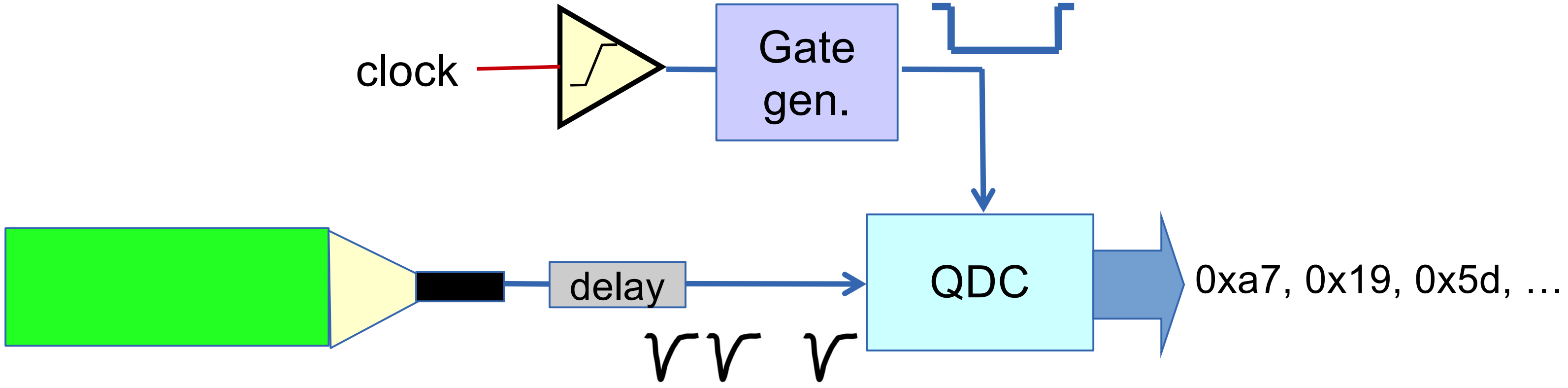
- But, what is the 1st peak?
  - How can we estimate it?





QDC: pedestal subtraction

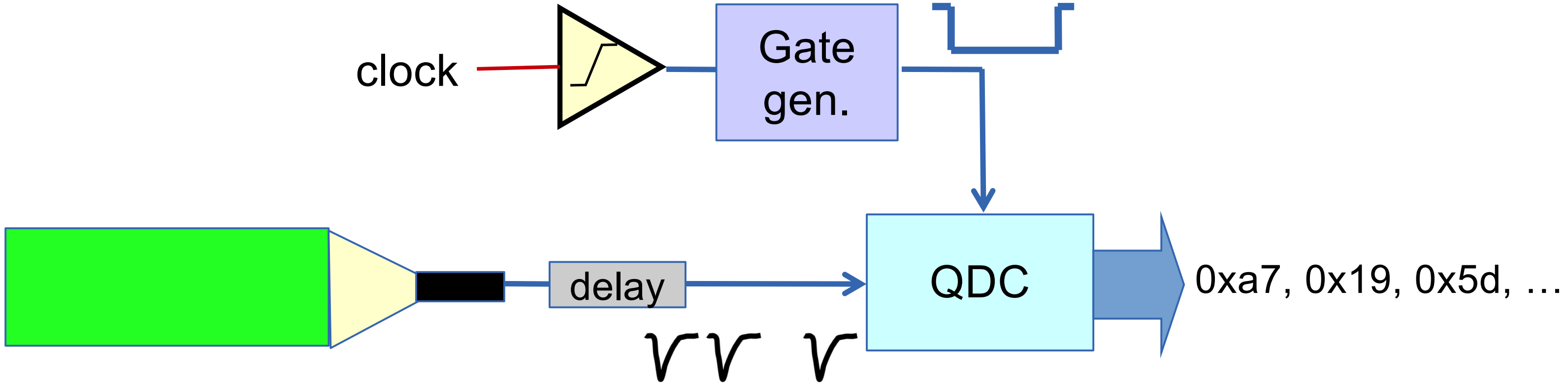
- The pedestal can be measured with an out-of-phase trigger
  - PMT dark current, thermal noise, Jitter, fluctuations on power supply..
  - The same noise enters our physics measurements and contributes with an offset to the distribution
- The result of a pedestal measurement has to be subtracted from our charge measurements



QDC: pedestal subtraction

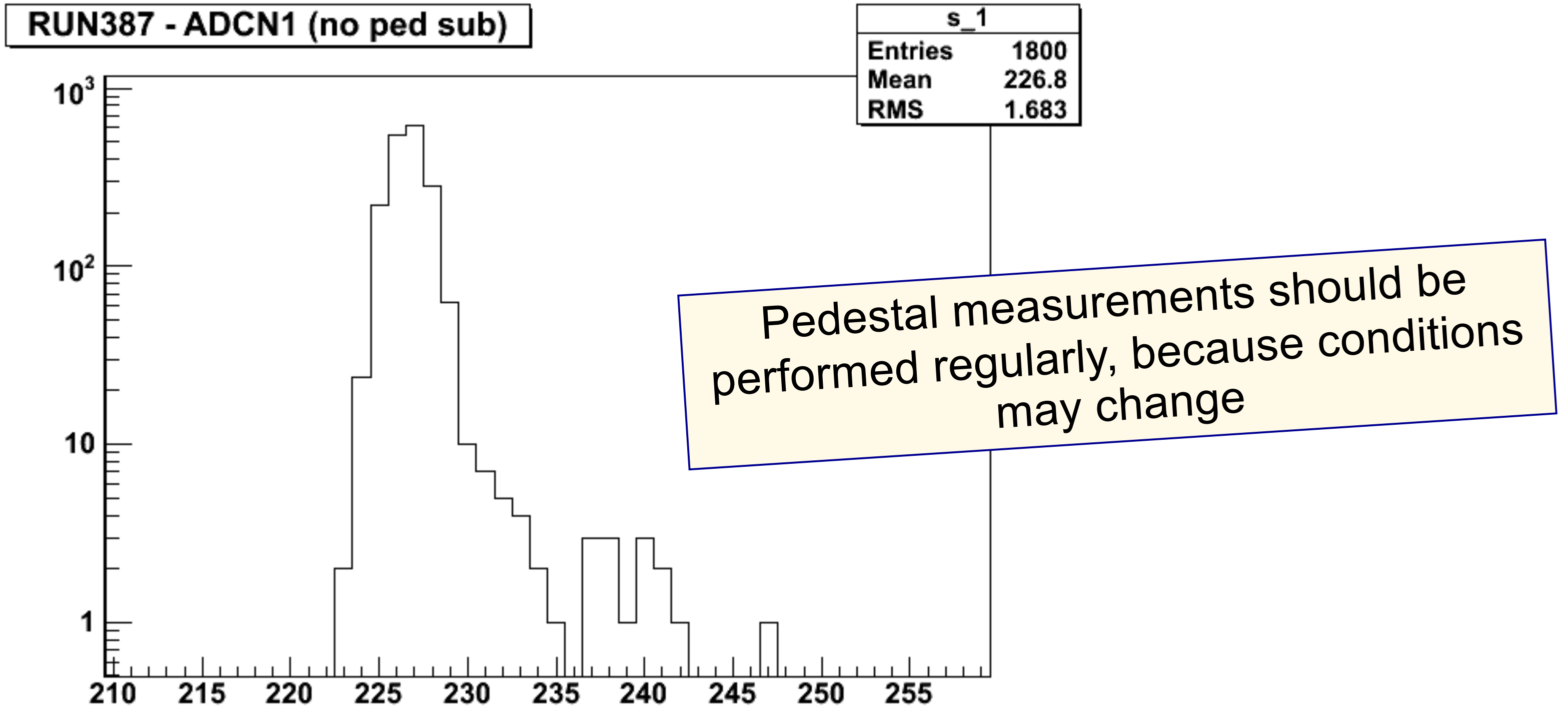
- The pedestal can be measured with an out-of-phase trigger
  - PMT dark current, thermal noise, Jitter, fluctuations on power supply..
  - The same noise enters our physics measurements and contributes with an offset to the distribution
- The result of a pedestal measurement has to be subtracted from our charge measurements

We essentially want to integrate the baseline of our setup



QDC: pedestal subtraction

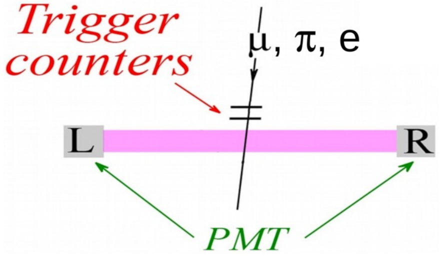
- The pedestal can be measured with an out-of-phase trigger
  - PMT dark current, thermal noise, Jitter, fluctuations on power supply..
  - The same noise enters our physics measurements and contributes with an offset to the distribution
- The result of a pedestal measurement has to be subtracted from our charge measurements

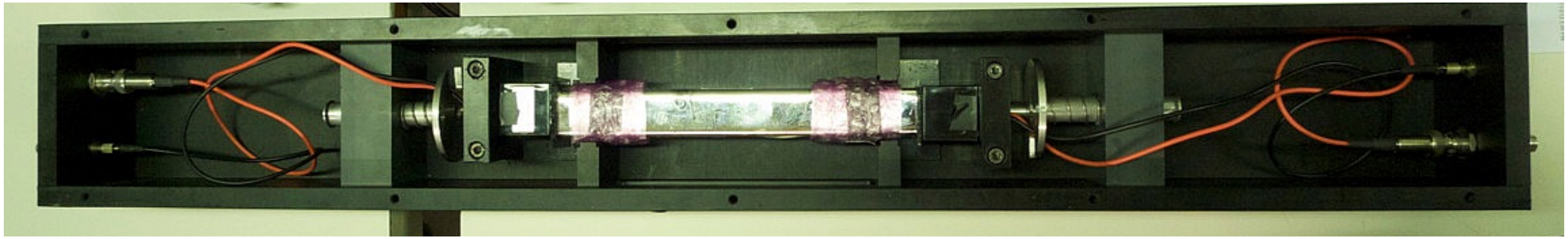


Pedestal measurements should be performed regularly, because conditions may change

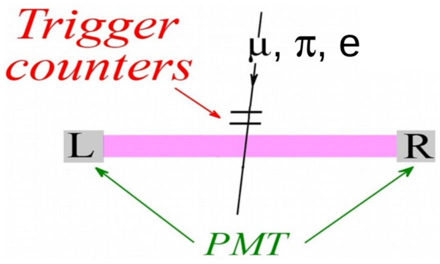
“Real” QDC at work

- PbWO$_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN



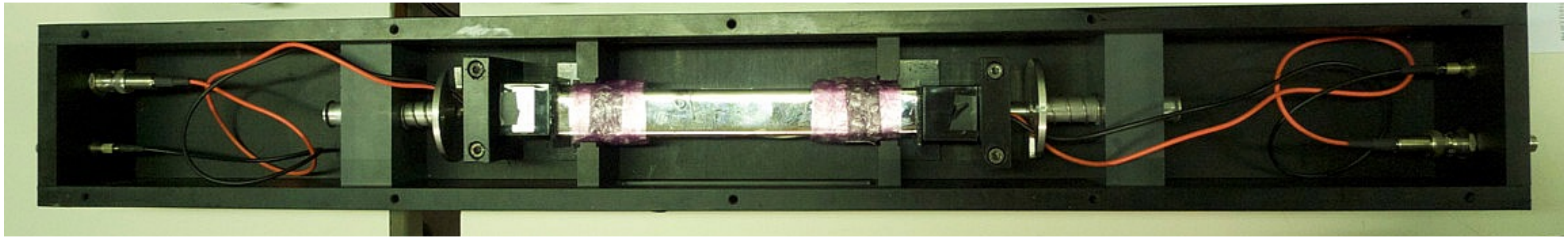


“Real” QDC at work

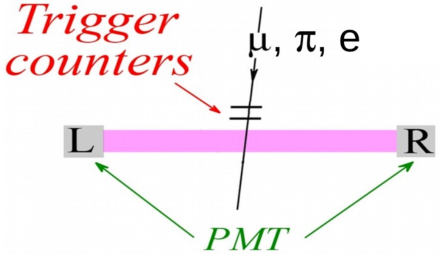


- PbWO$_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN

- A lot of effects will sum-up in a realistic case, like a test-beam
  - We can’t feed our detector signal directly to the ADC (or QDC)
  - We have PMTs, transmission lines (with signal losses!), power supply fluctuations, impedance mismatches, reflections, distortions, etc..

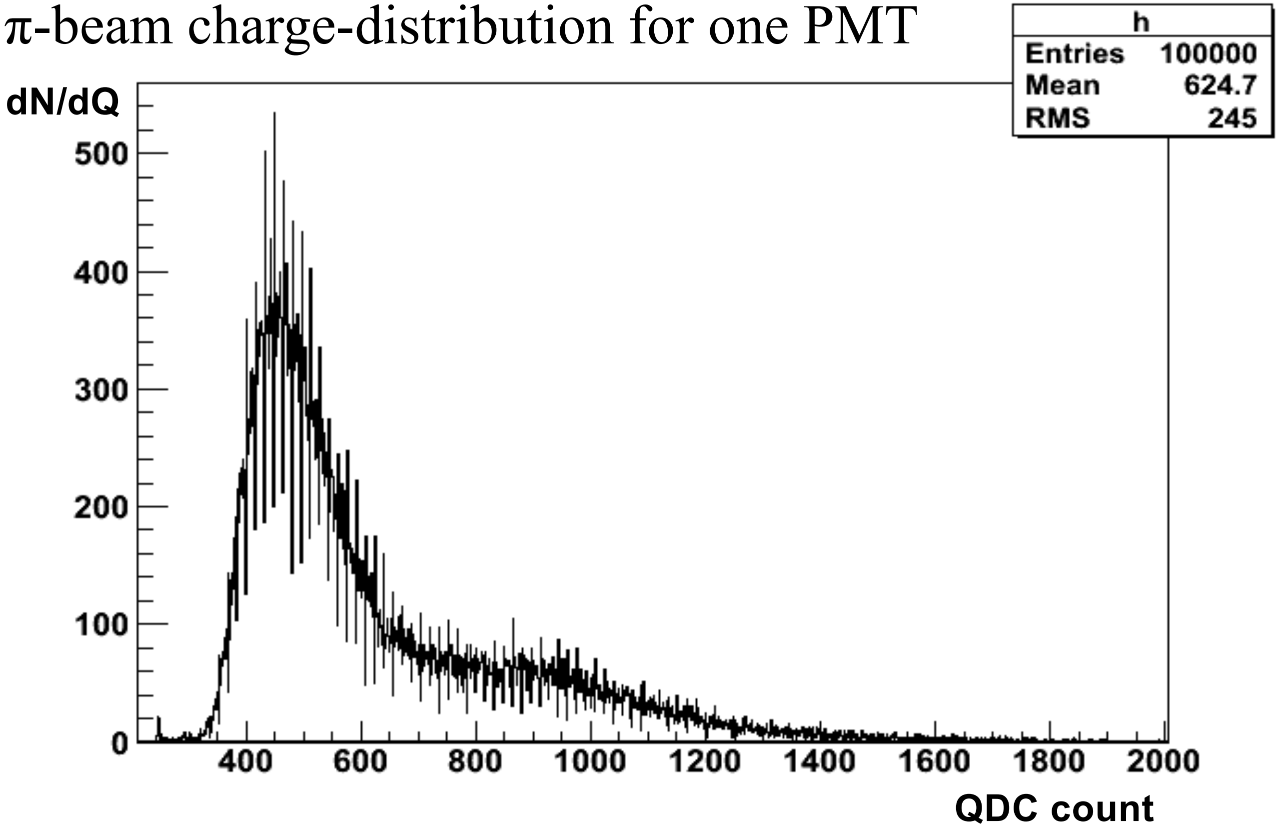


“Real” QDC at work



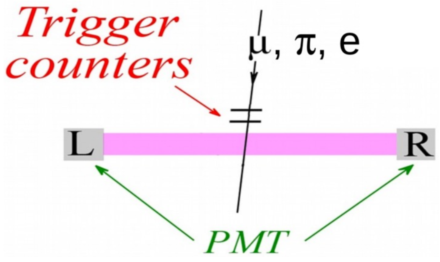
- $PbWO_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN

π-beam charge-distribution for one PMT

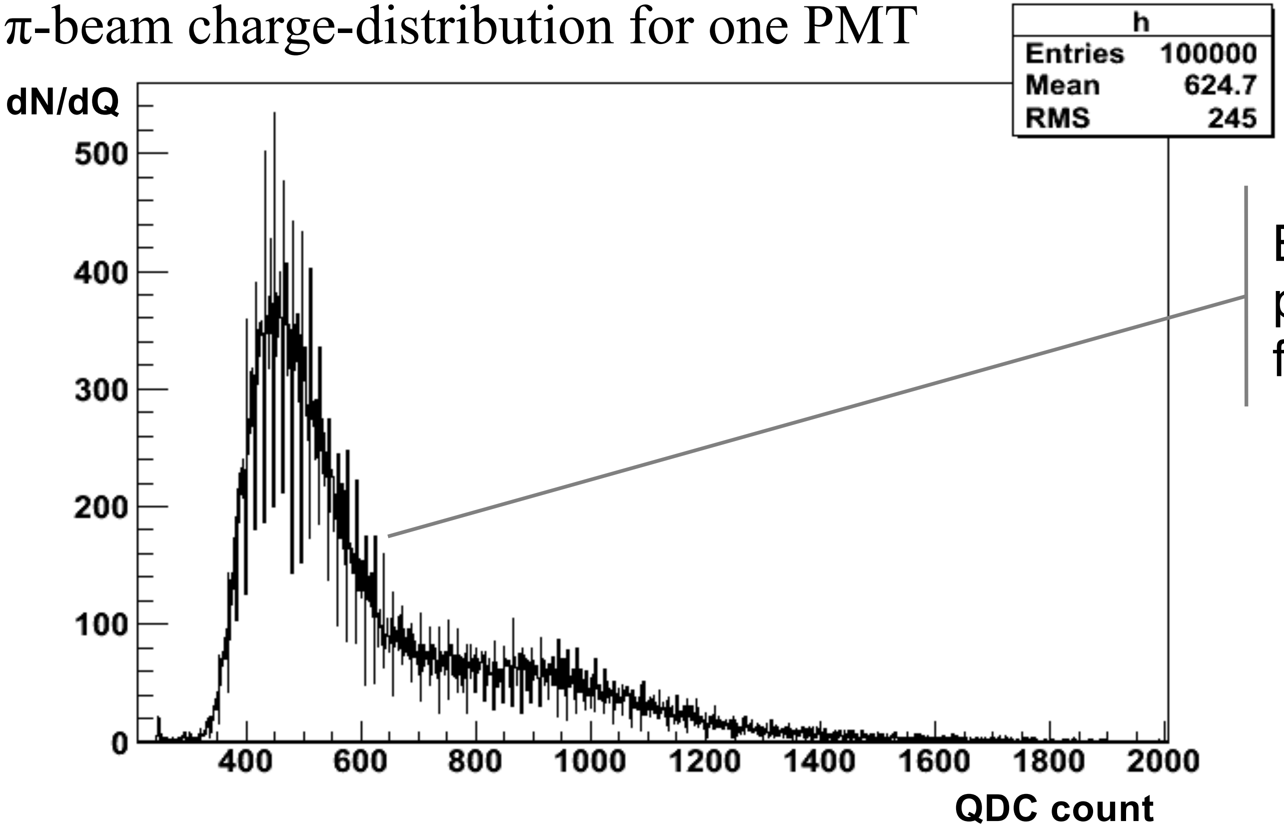


"Real" QDC at work

- $PbWO_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN



π-beam charge-distribution for one PMT

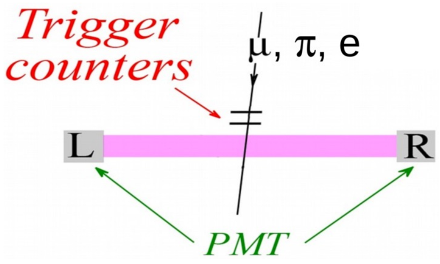


But, what are all those little peaks? Just statistical fluctuations?

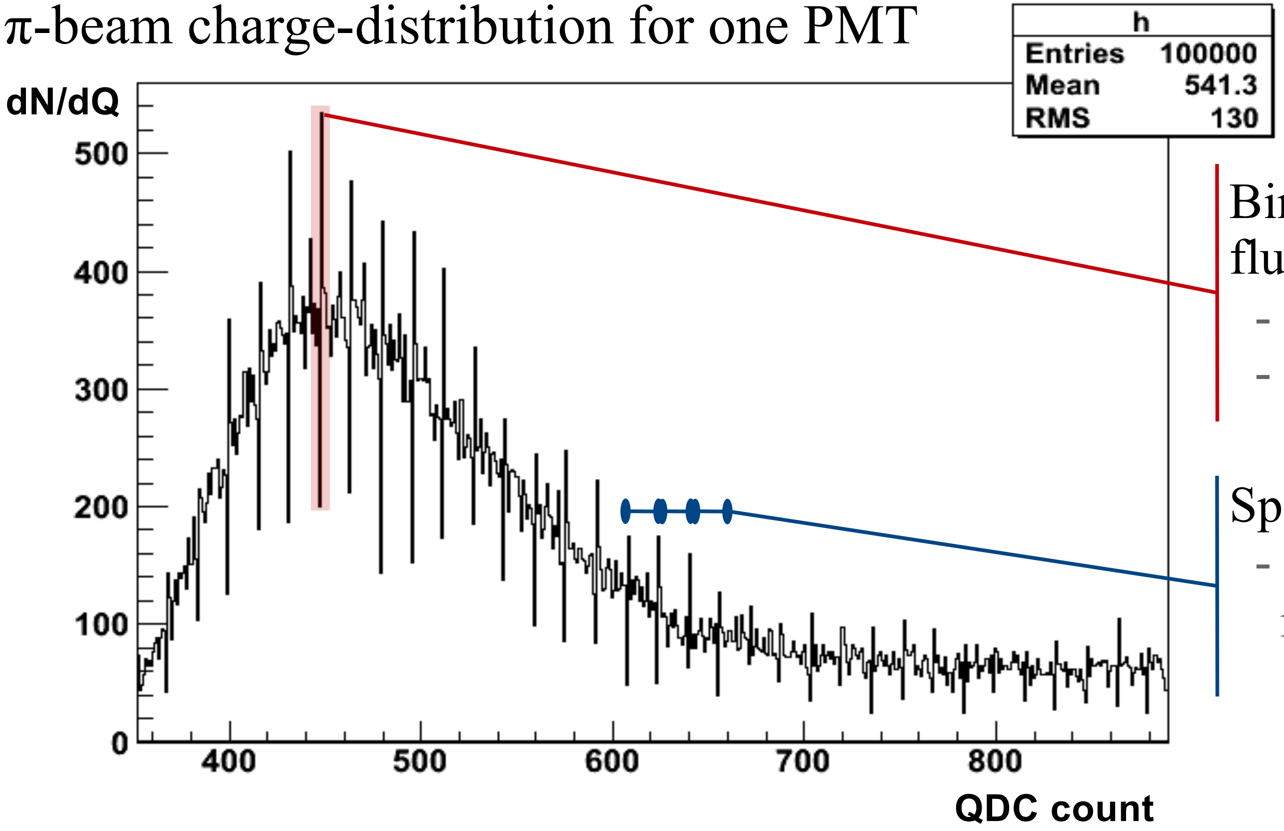
Let's zoom in!

"Real" QDC at work

- $PbWO_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN



π-beam charge-distribution for one PMT



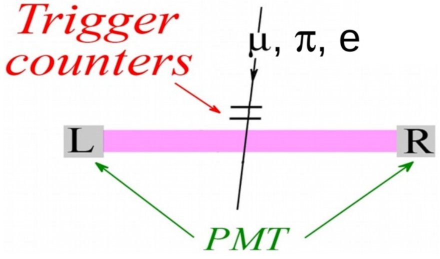
Bin with N entries can fluctuate with $\sigma = \sqrt{N}$
- expected $\sigma=\sqrt{360}\sim19$
- observed ~200 (>10 σ)

Spikes are regularly distributed
- Some systematic effect must be taking place

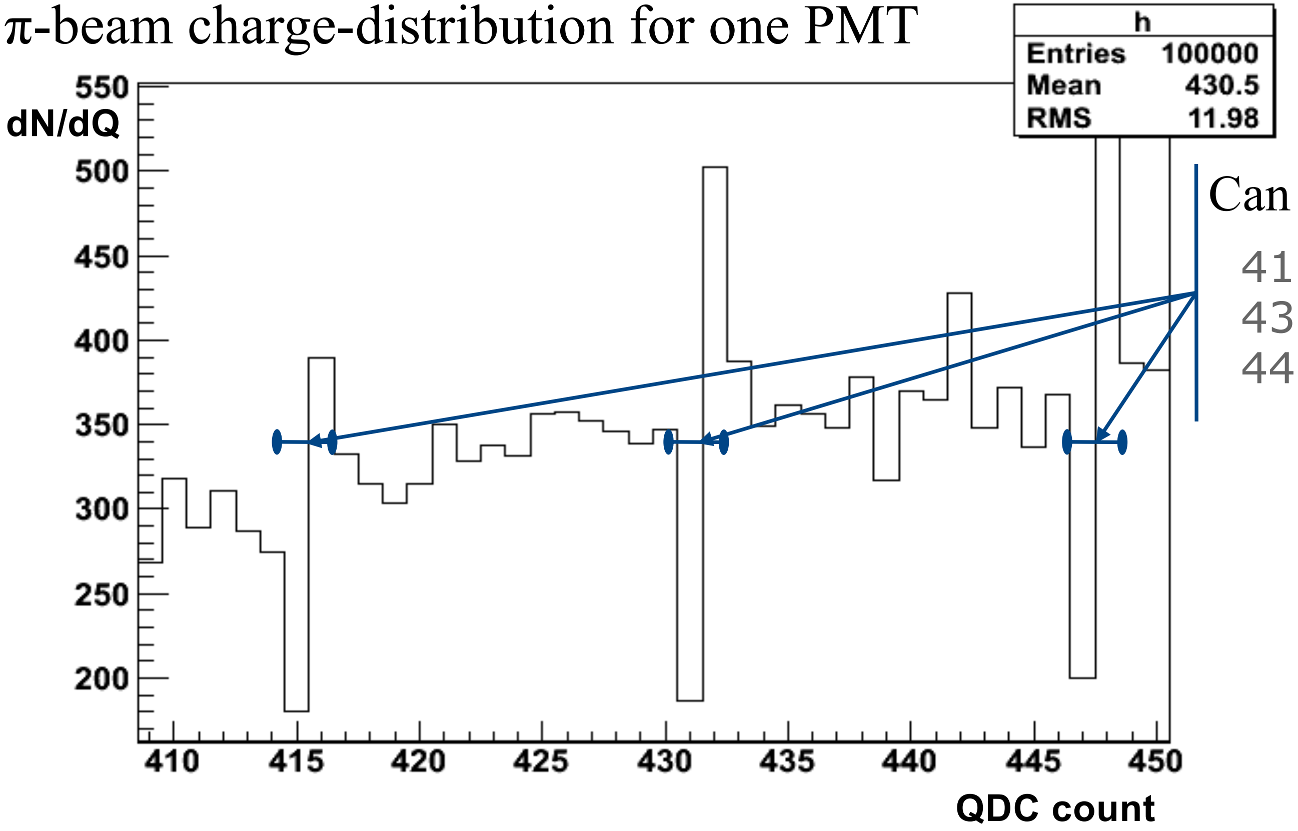
Let's zoom in!

“Real” QDC at work

- PbWO$_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN



π-beam charge-distribution for one PMT

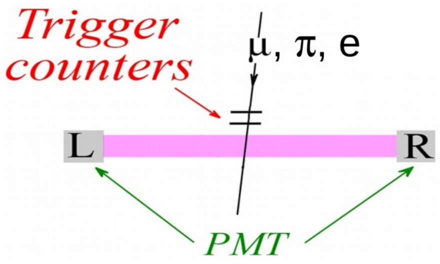


Can you see the effect?

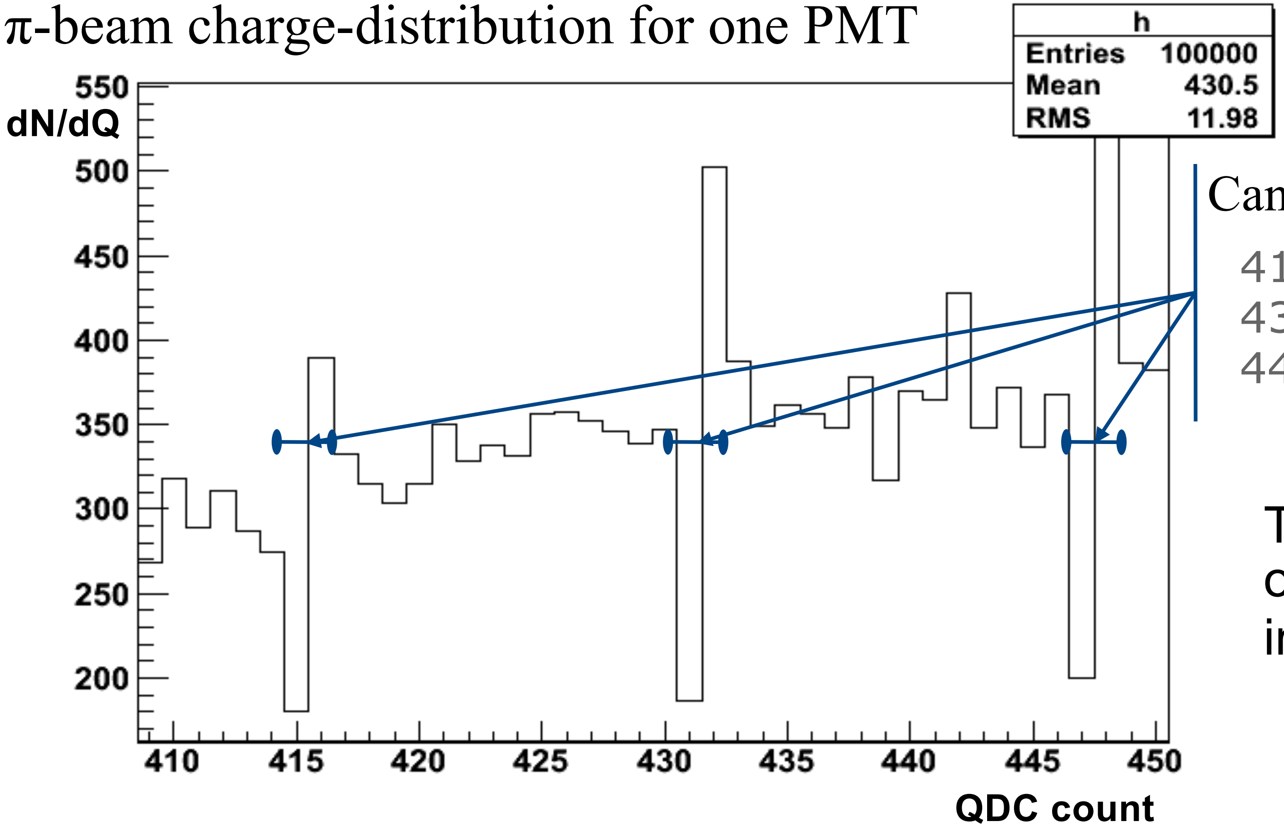
415 & 416 –
431 & 432 –
447 & 448 –

“Real” QDC at work

- PbWO$_4$ scintillating crystal equipped with two PMTs and exposed to e, μ and π beams
  - Real data from a test beam @CERN



π-beam charge-distribution for one PMT



Can you see the effect?

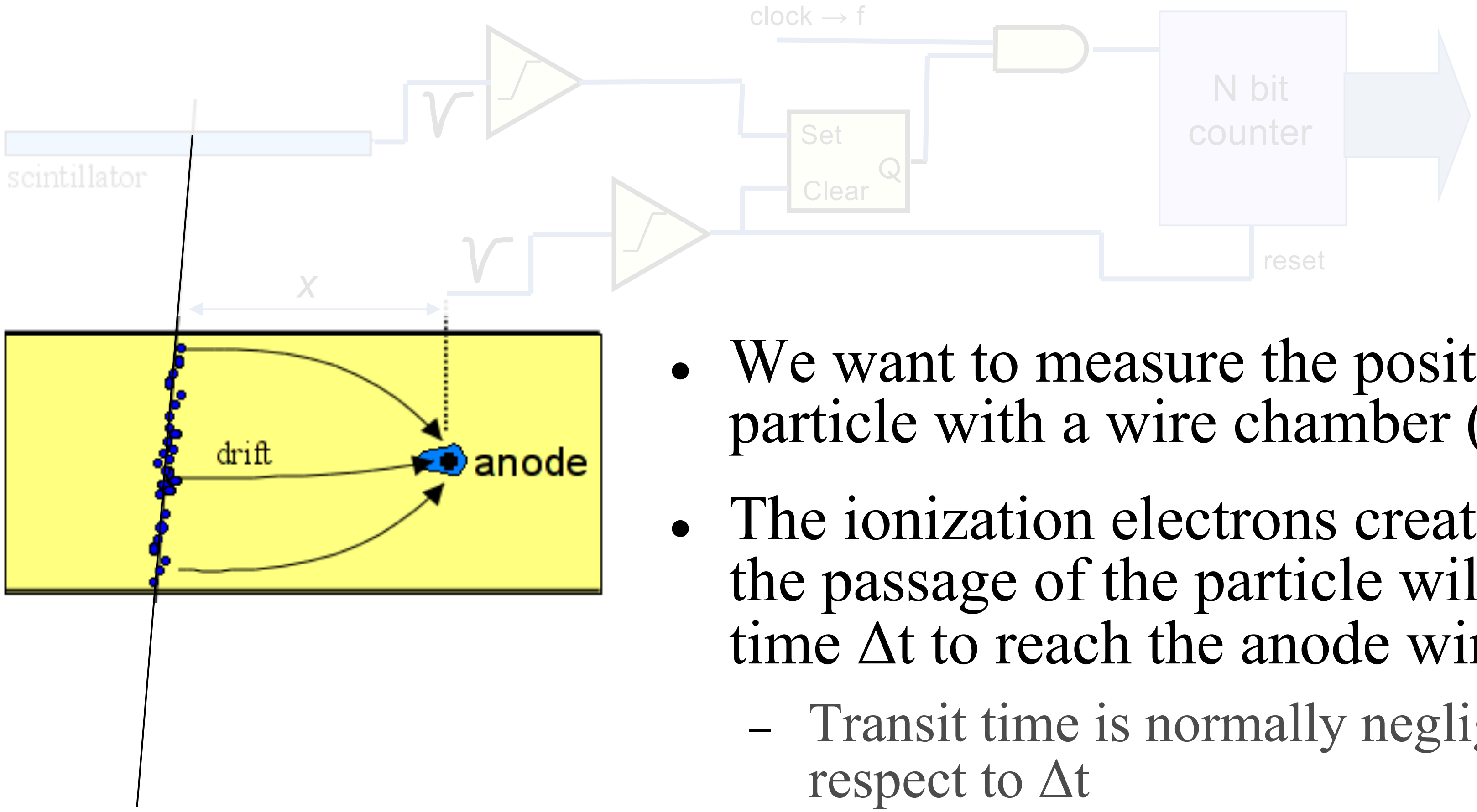
415 & 416 → 0x19**f** & 0x1A**0**
431 & 432 → 0x1A**f** & 0x1B**0**
447 & 448 → 0x1B**f** & 0x1C**0**

The QDC prefers
output of type `0x...0`
in respect of `0x...f`

Outline

- Introduction
  - DAQ, Electronics & Readout Chain
- Measure energy deposition
  - Scintillator setup
  - Photomultiplier
  - Analog-to-Digital conversion
  - Charge-to-Digital conversion
  - QDC in real life
- Measure position
  - Wire chamber setup
  - Time-to-Digital conversion
  - TDC in real life
- Corollary

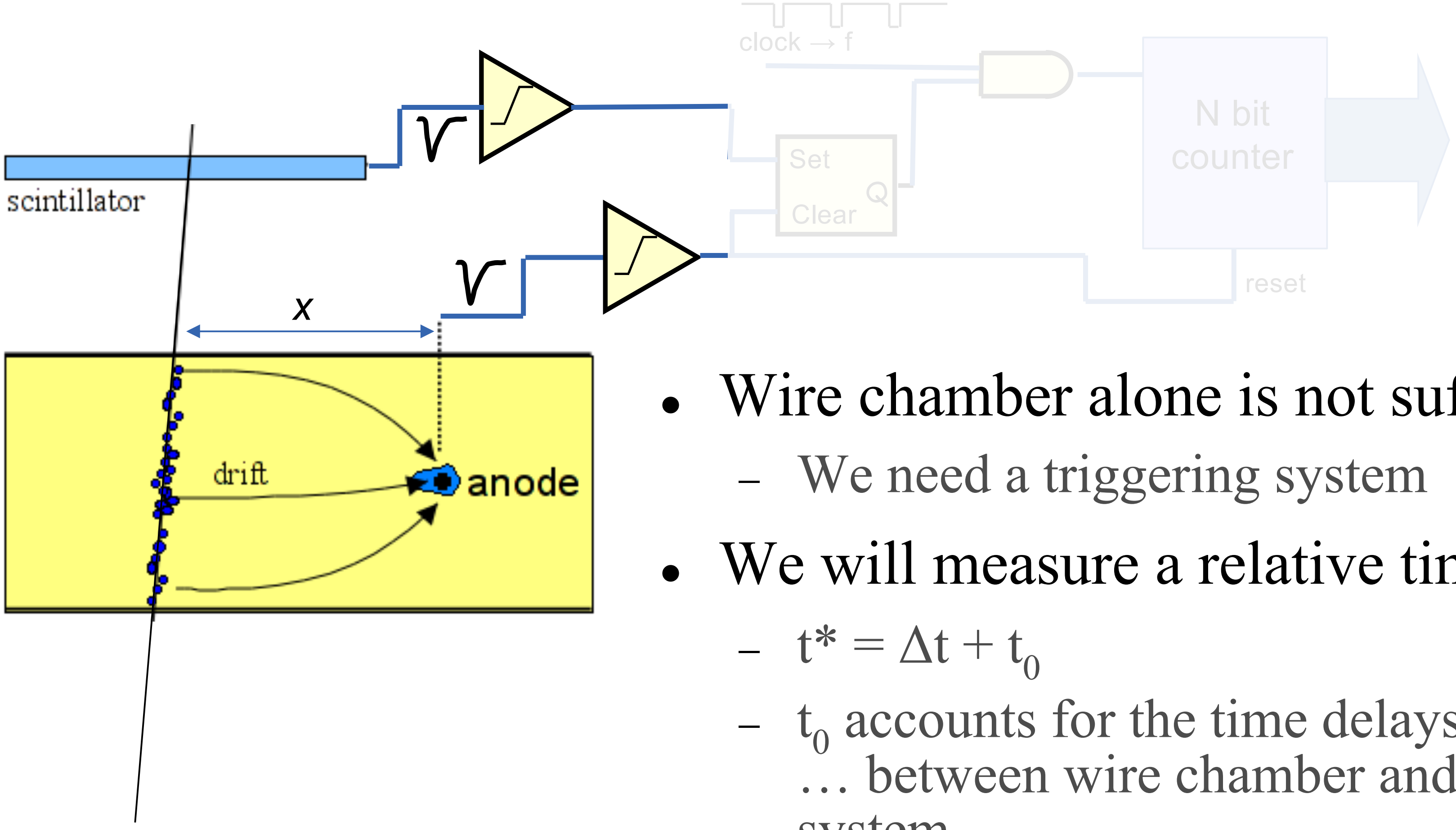
Position measurement



- We want to measure the position of particle with a wire chamber (**drift**)
- The ionization electrons created by the passage of the particle will take a time Δt to reach the anode wire
  - Transit time is normally negligible with respect to Δt
  - If we consider a constant drift speed v_D (e.g.: 50 µm/ns), then position is:

$$\mathbf{x = v_D \cdot \Delta t}$$

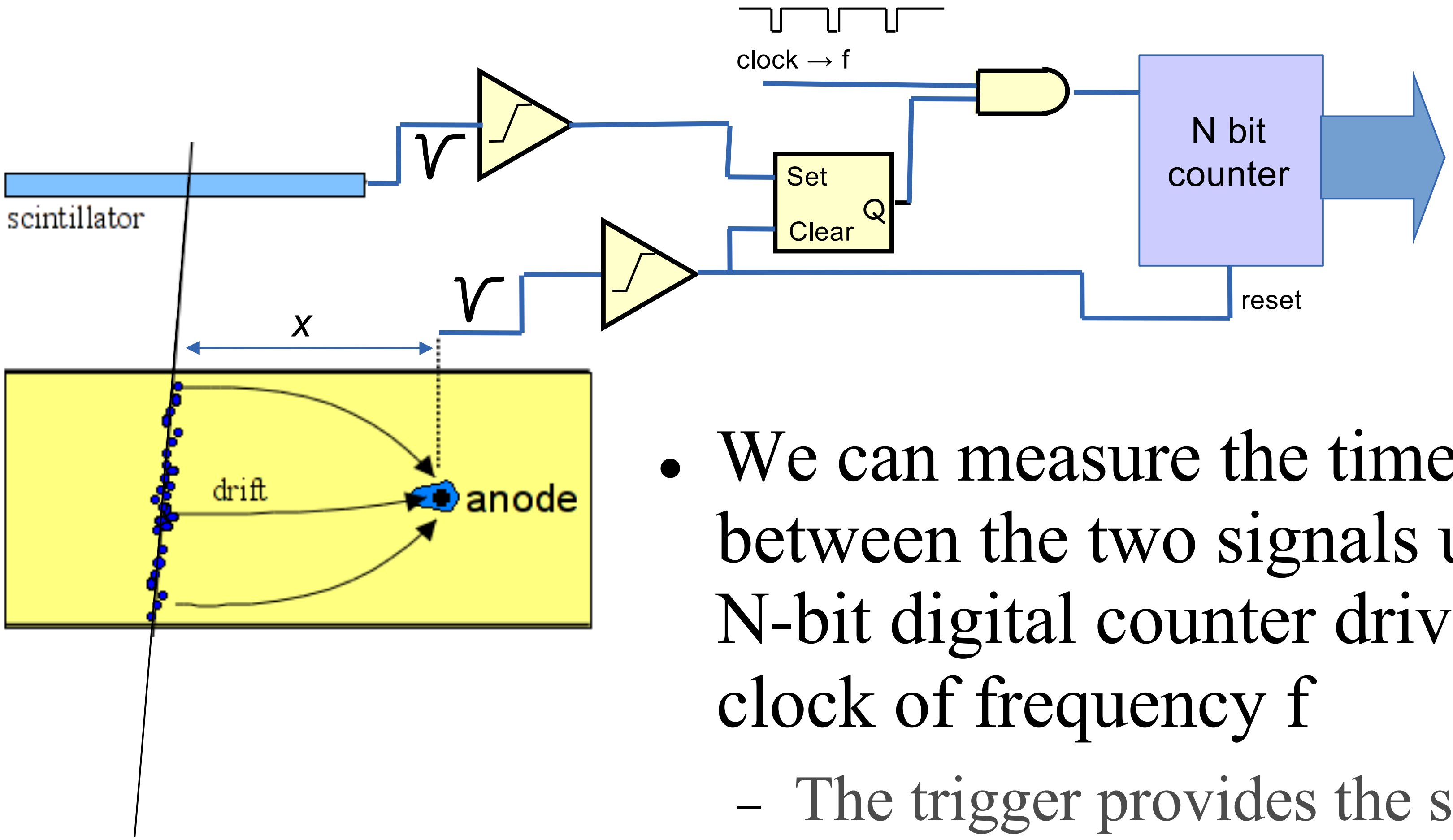
Triggering



- Wire chamber alone is not sufficient
  - We need a triggering system
- We will measure a relative time
  - $t^* = \Delta t + t_0$
  - t_0 accounts for the time delays, offsets, … between wire chamber and triggering system
- Assuming a constant drift

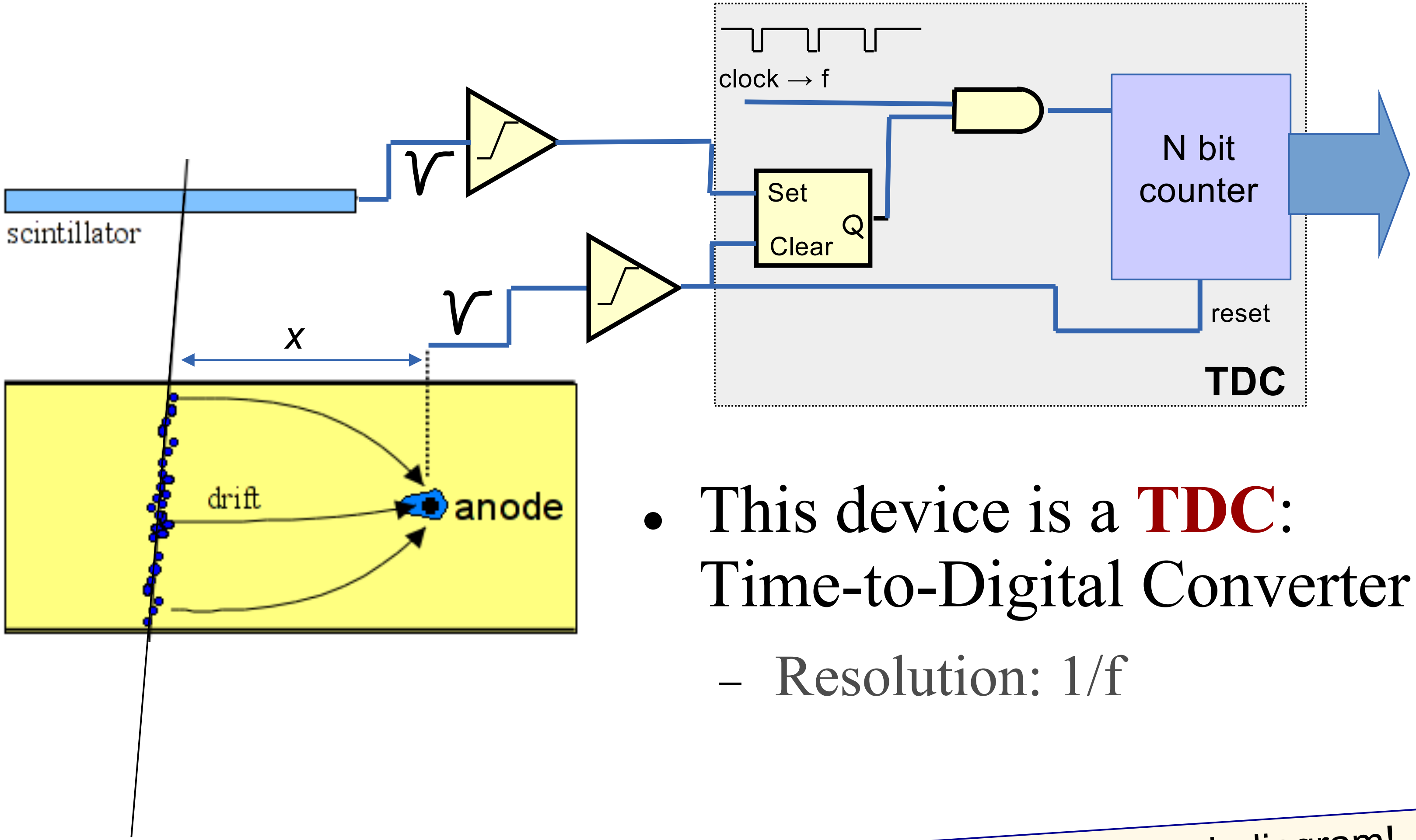
$$x = \alpha t^* + \beta$$

Time measurement

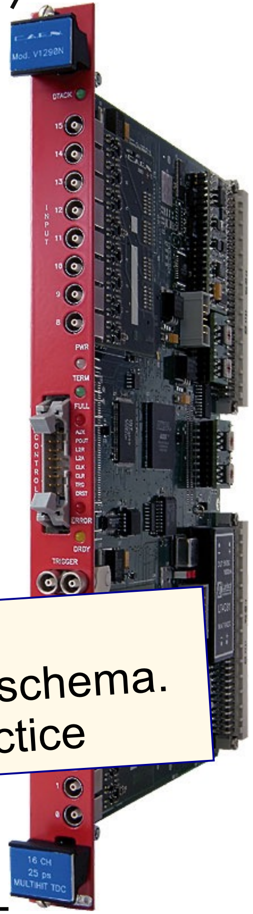


- We can measure the time offset between the two signals using a N-bit digital counter driven by a clock of frequency f
  - The trigger provides the start signal
  - Wire signal acts as a stop signal

Time measurement: TDC

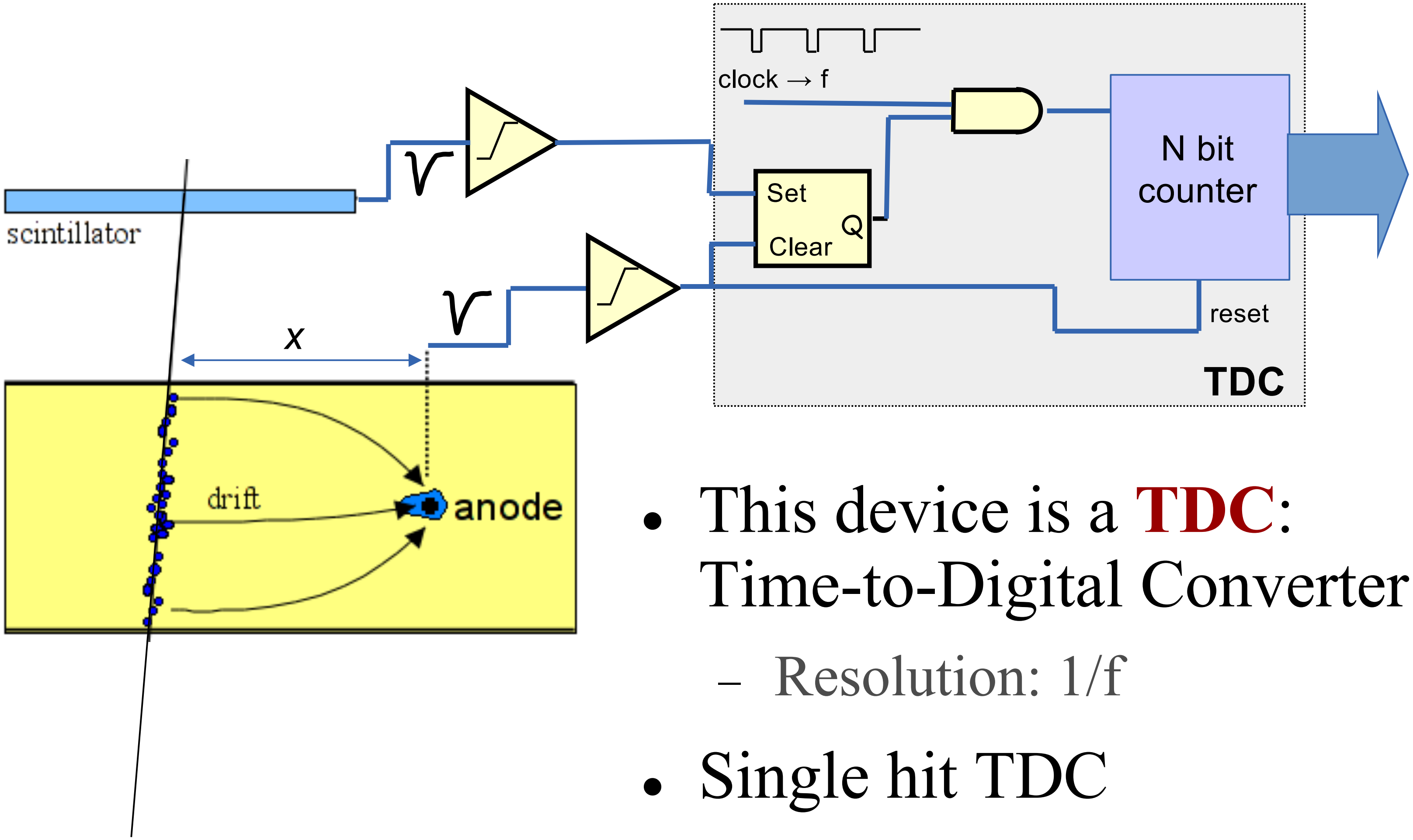


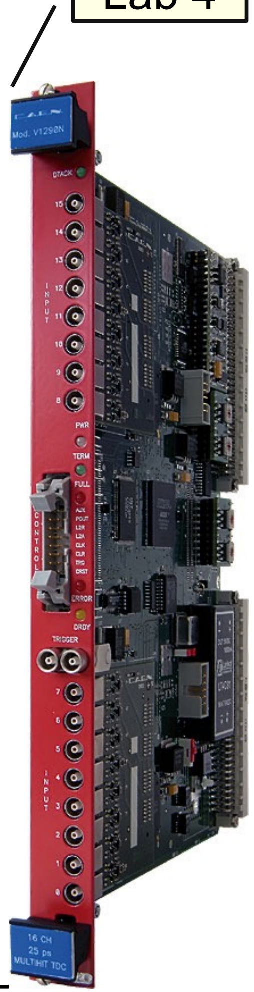
- This device is a **TDC**: Time-to-Digital Converter
  - Resolution: 1/f


Lab 4

Very simplified block diagram!
Many complicated parts not present on the schema.
Clock gating is NOT a good design practice

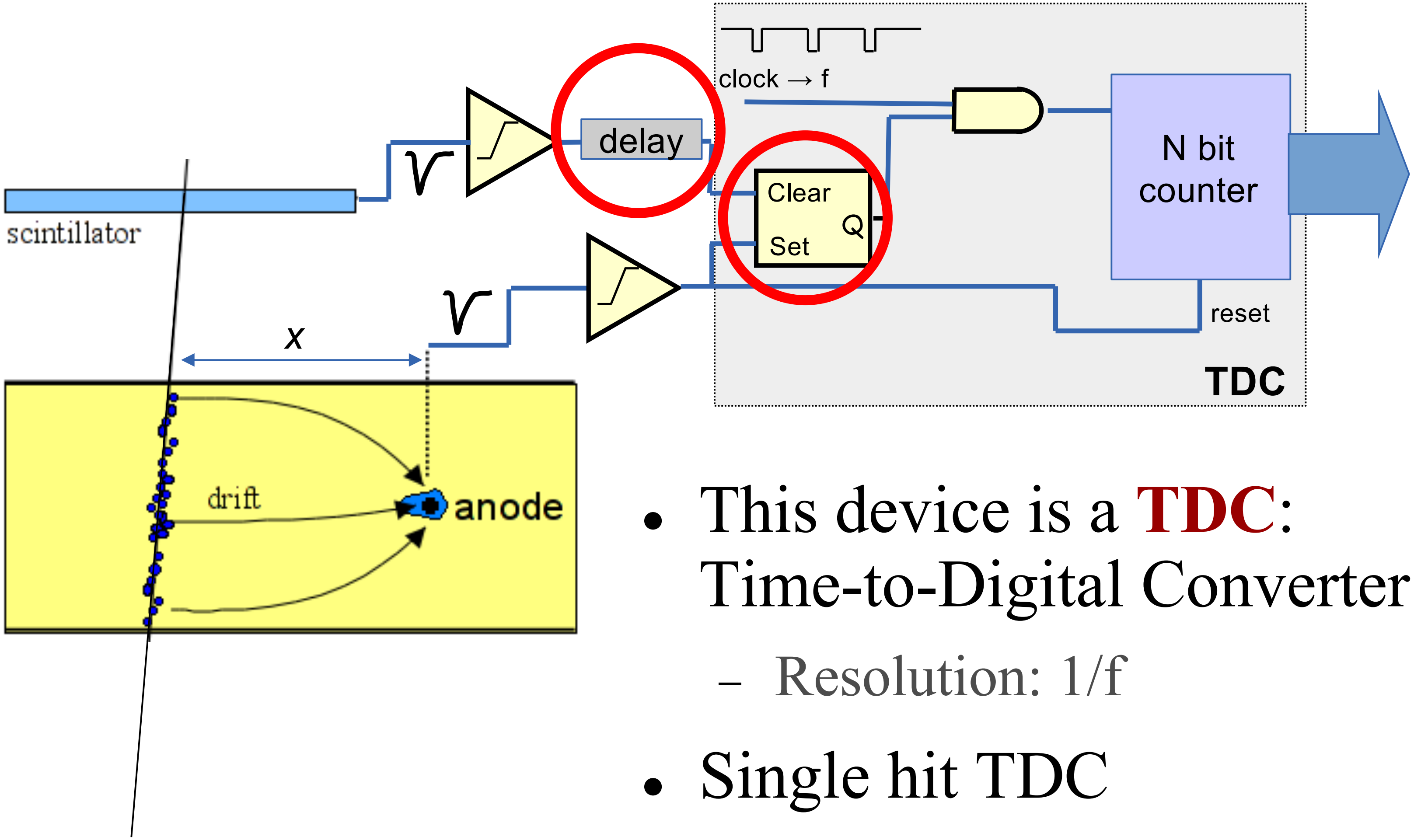
Time measurement: TDC



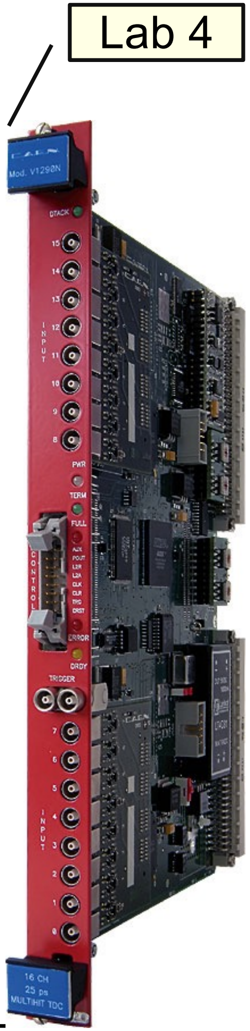


- This device is a **TDC**: Time-to-Digital Converter
  - Resolution: 1/f
- Single hit TDC
  - if a noise spike comes just before the wire signal, the measure is lost

Time measurement: TDC

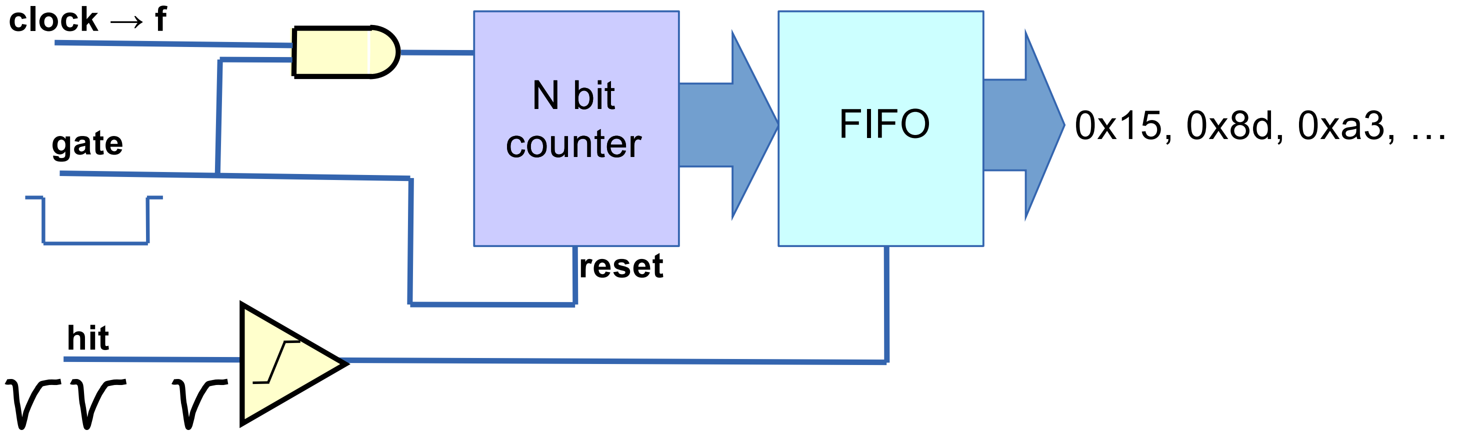


- This device is a **TDC**: Time-to-Digital Converter
  - Resolution: 1/f
- Single hit TDC
  - if a noise spike comes just before the wire signal, the measure is lost



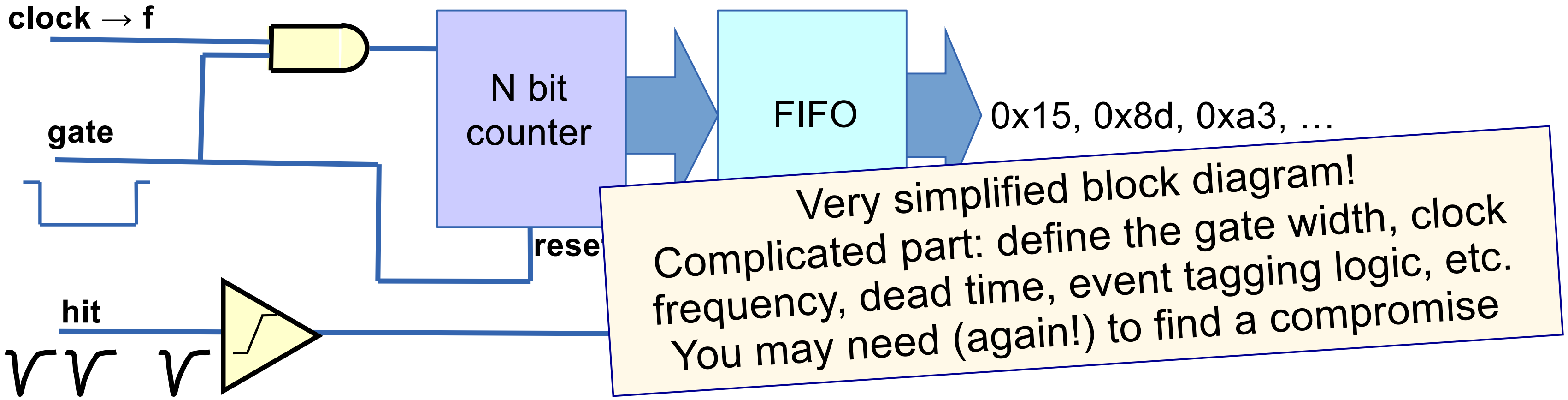
Multi-hit TDC

- Gate resets and starts the counter
  - It also provides the measurement period
- Each “hit” (i.e. signal) forces the FIFO to load the current value of the counter, that is the delay after the gate start
  - Common-start configuration
  - In order to distinguish between hits belonging to different gates, some additional logic is need to tag the data



Multi-hit TDC

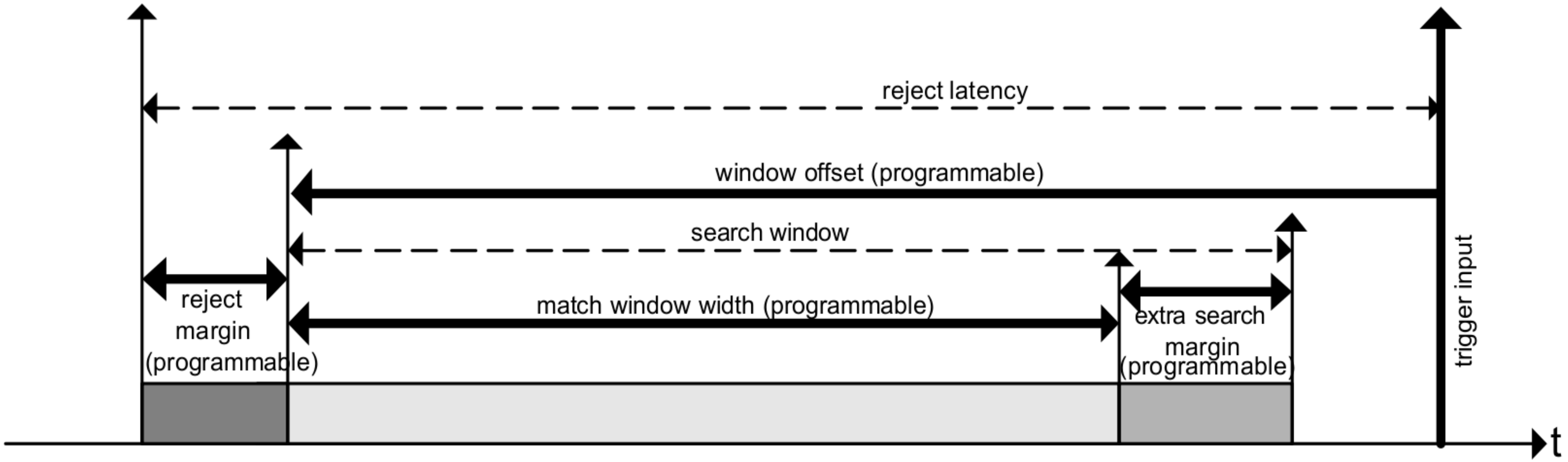
- Gate resets and starts the counter
  - It also provides the measurement period
- Each “hit” (i.e. signal) forces the FIFO to load the current value of the counter, that is the delay after the gate start
  - Common-start configuration
  - In order to distinguish between hits belonging to different gates, some additional logic is need to tag the data



Very simplified block diagram!
Complicated part: define the gate width, clock frequency, dead time, event tagging logic, etc.
You may need (again!) to find a compromise

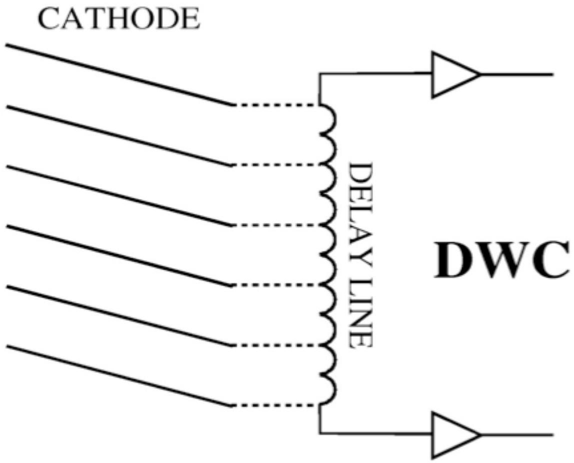
Actual TDCs

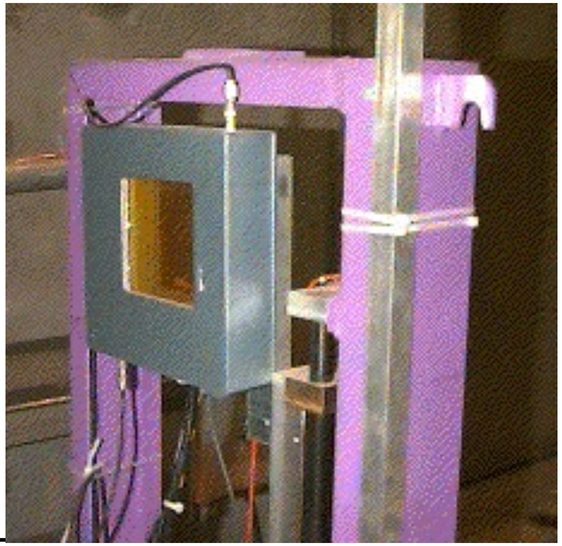
- Plenty of TDCs architectures available on the market
  - Common Start, Common Stop, Charging Capacitor, Vernier, etc.
- Real TDCs provide advanced functionalities for fine-tuning the hit-trigger matching
  - Internal programmable delays or generation of programmable gates
  - Programmable rejection frames
  - Usually via a dedicated C library/API



Real life wire chamber & TDC

- XDWC: delay wire chambers
  - used on the SPS extracted lines to measure beam profiles
- Two cathode planes provide X and Y positions
  - Measurement based on the delay gained along a delay line

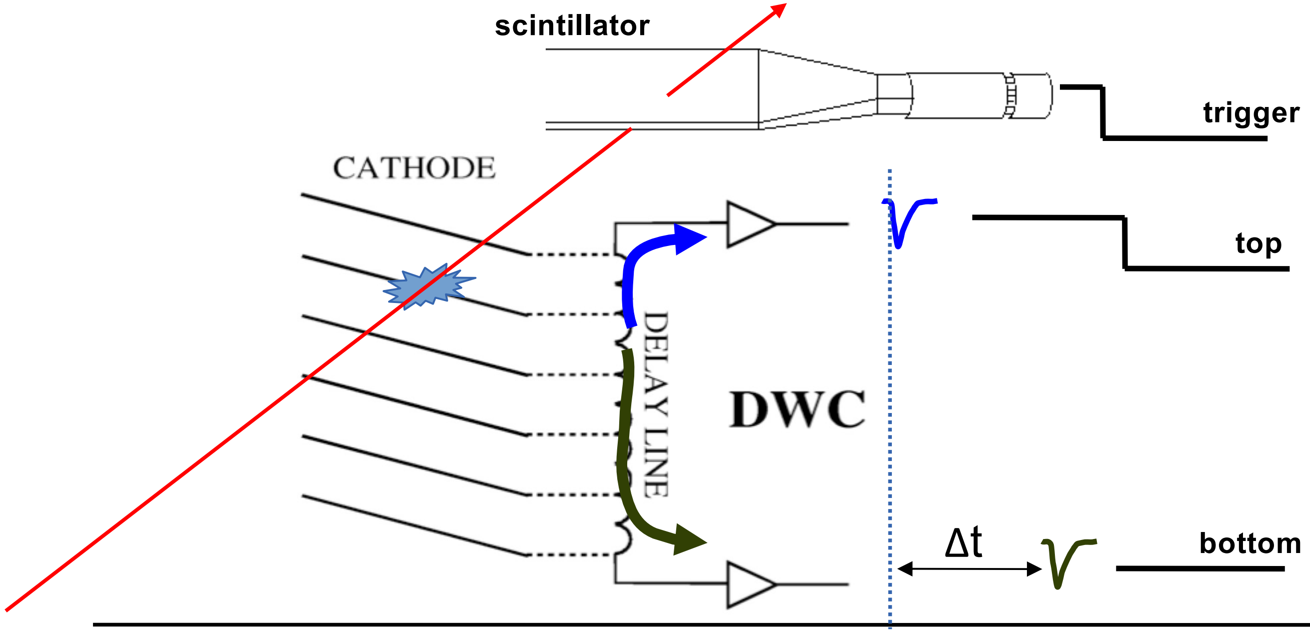


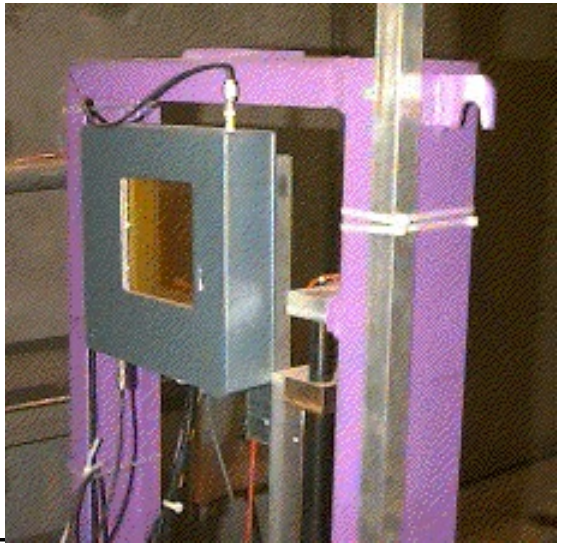


Real life wire chamber & TDC

- XDWC: delay wire chambers
  - used on the SPS extracted lines to measure beam profiles
- Two cathode planes provide X and Y positions
  - Measurement based on the delay gained along a delay line

$$y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$$

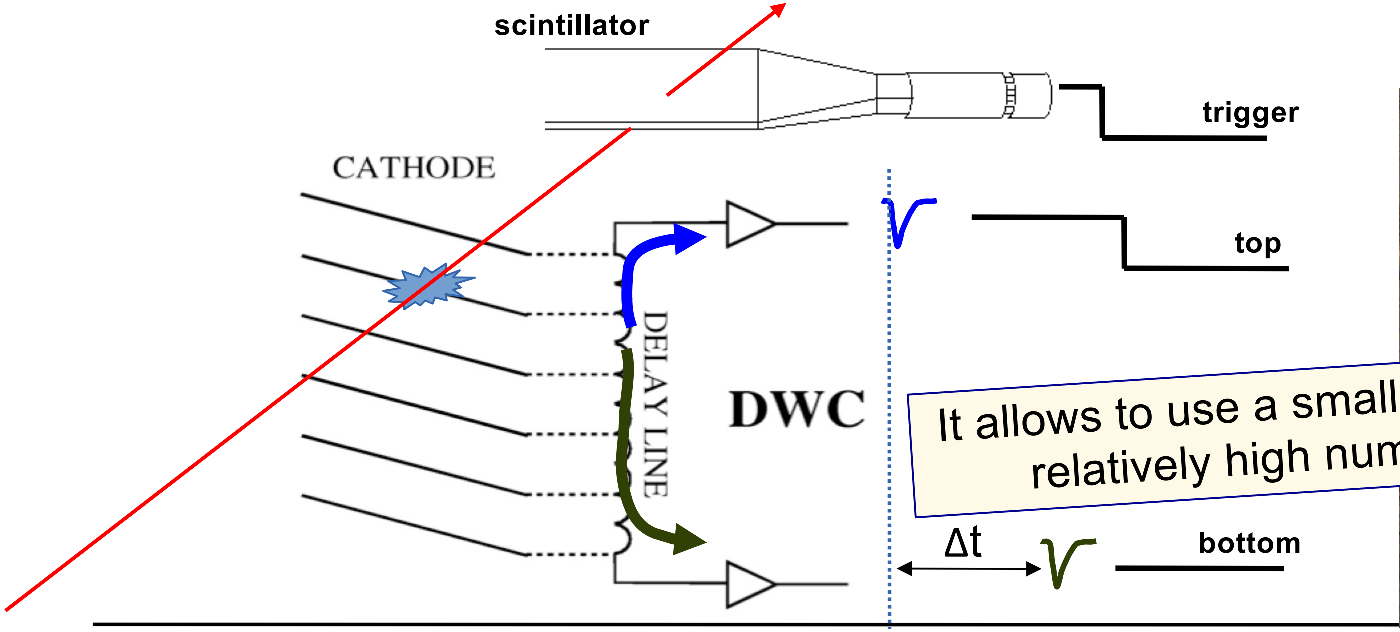


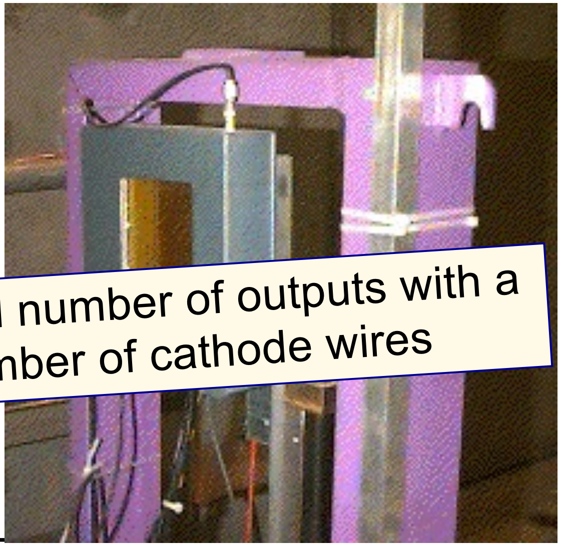


Real life wire chamber & TDC

- XDWC: delay wire chambers
  - used on the SPS extracted lines to measure beam profiles
- Two cathode planes provide X and Y positions
  - Measurement based on the delay gained along a delay line

$$y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$$

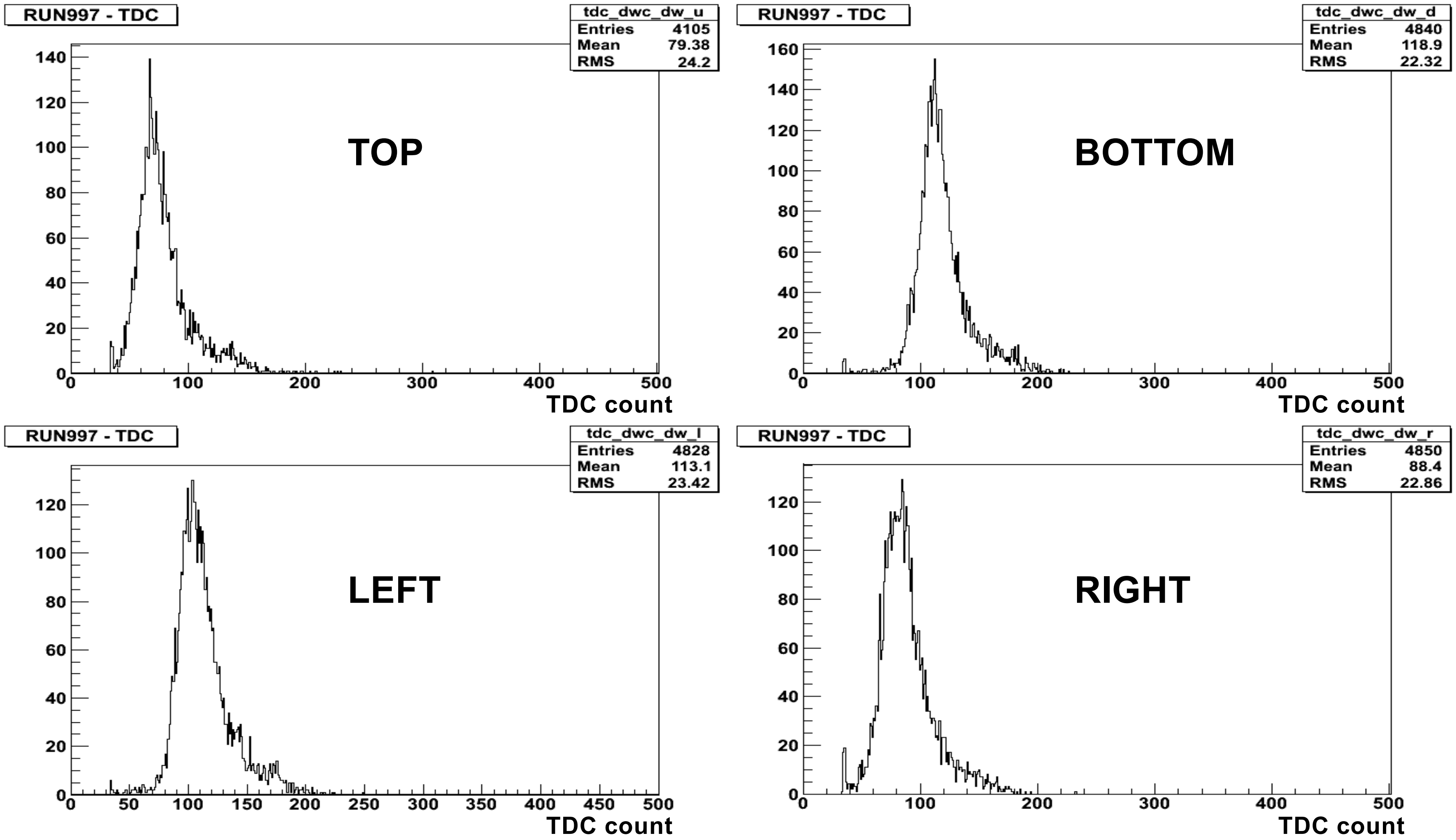




It allows to use a small number of outputs with a relatively high number of cathode wires

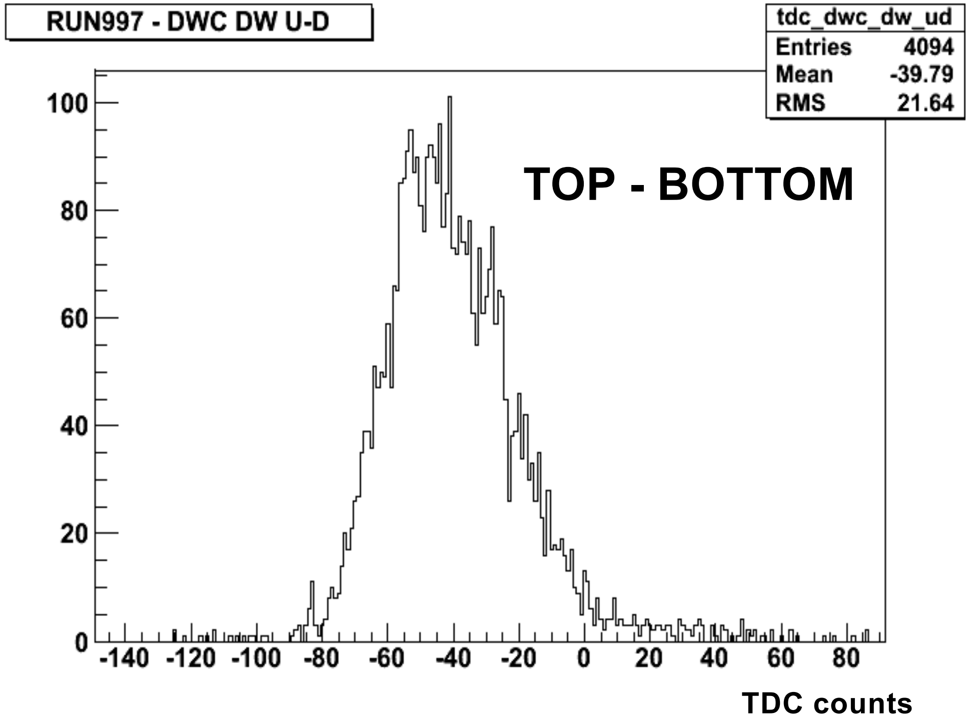
Raw time data

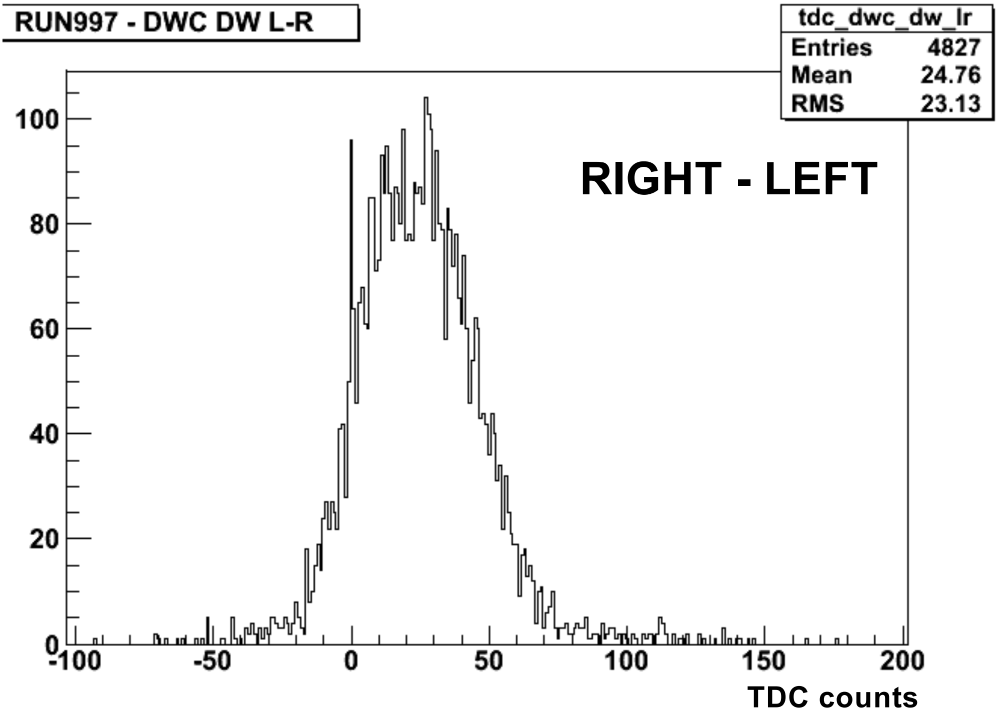
- Take a run (some thousands events)
  - Individual channel distribution



Un-calibrated beam profile

- Beam sizes are still in TDC counts
  - Not very useful, though
  - How do we convert this into a known scale (e.g. cm)?





Outline

- Introduction
  - DAQ, Electronics & Readout Chain
- Measure energy deposition
  - Scintillator setup
  - Photomultiplier
  - Analog-to-Digital conversion
  - Charge-to-Digital conversion
  - QDC in real life
- Measure position
  - Wire chamber setup
  - Time-to-Digital conversion
  - TDC in real life
- Corollary: calibration

Calibration

- Previous experiments provide relative measurements
  - Values obtained via our systems are in some (known) relation with the interesting quantities
    - Scintillator $Q \propto N_\gamma \propto E$
    - XDWC $y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$
- Our instruments need to be calibrated in order to give us the answer we are looking for
  - We have to determine the **parameters** that transform the raw data into a physics quantity
  - The parameters normally depend on the experimental setup (e.g. cable length, delay settings, HV settings, …)
  - Sometimes these parameters might depend on the detector itself (e.g. ageing of a scintillator may influence efficiency, light yield,...)

Calibration

- Previous experiments provide relative measurements
  - Values obtained via our systems are in some (known) relation with the interesting quantities
    - Scintillator $Q \propto N_\gamma \propto E$
    - XDWC $y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$
- Our instruments order to give us the ans
  - We ha the **parameters** that transform the raw data into a physics quantity
  - The parameters normally depend on the experimental setup (e.g. cable length, delay settings, HV settings, …)
  - Sometimes these parameters might depend on the detector itself (e.g. ageing of a scintillator may influence efficiency, light yield,...)

However, we still don’t know the proportionality factor between charge and energy, or between time and position

Calibration

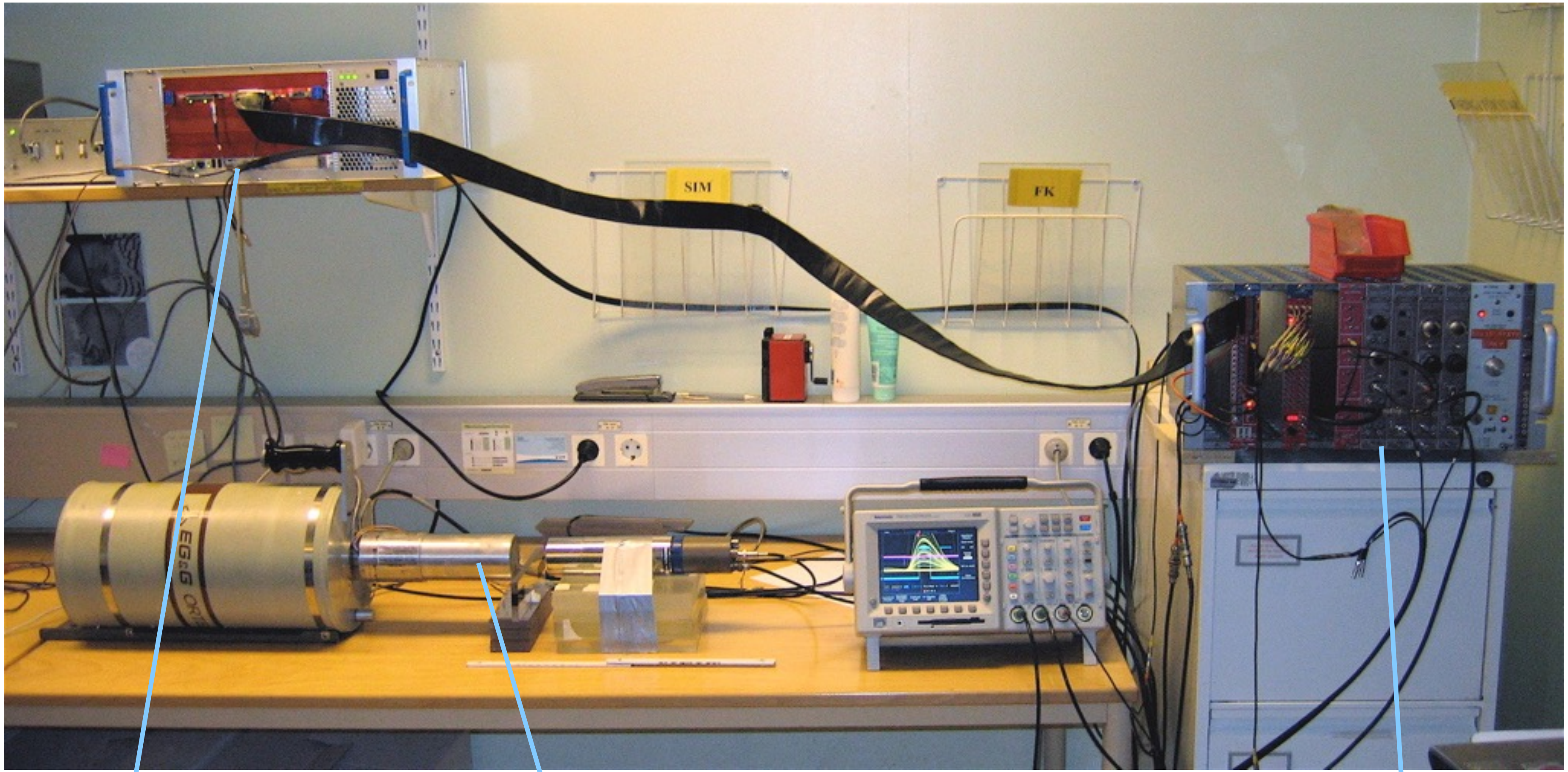
- Previous experiments provide relative measurements
  - Values obtained via our systems are in some (known) relation with the interesting quantities
    - Scintillator $Q \propto N_\gamma \propto E$
    - XDWC $y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$
- Our instruments need to be calibrated in order to give us the answer we are looking for
  - We have to determine the **parameters** that transform the raw data into a physics quantity
  - The parameters normally depend on the experimental setup (e.g. cable length, delay settings, HV settings, …)
  - Sometimes these parameters might depend on the detector itself (e.g. ageing of a scintillator may influence efficiency, light yield,...)

Calibration

- Previous experiments provide relative measurements
  - Values obtained via our systems are in some (known) relation with the interesting quantities
    - Scintillator $Q \propto N_\gamma \propto E$
    - XDWC $y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t$ $+ \beta$
- Our instruments need to be ve us the answer we ar
  - W ansform the raw c
  - T ually depend on the experimental setup (e. ength, delay settings, HV settings, …)
  - Sometimes these parameters might depend on the detector itself (e.g. ageing of a scintillator may influence efficiency, light yield,...)

N.B.: calibration mechanisms/procedures shall be always foreseen in the design of our detector and DAQ

E.g.: Ge Crystal for isotope ID



Trigger and front-end

Crystal HPGe
Radiation detector

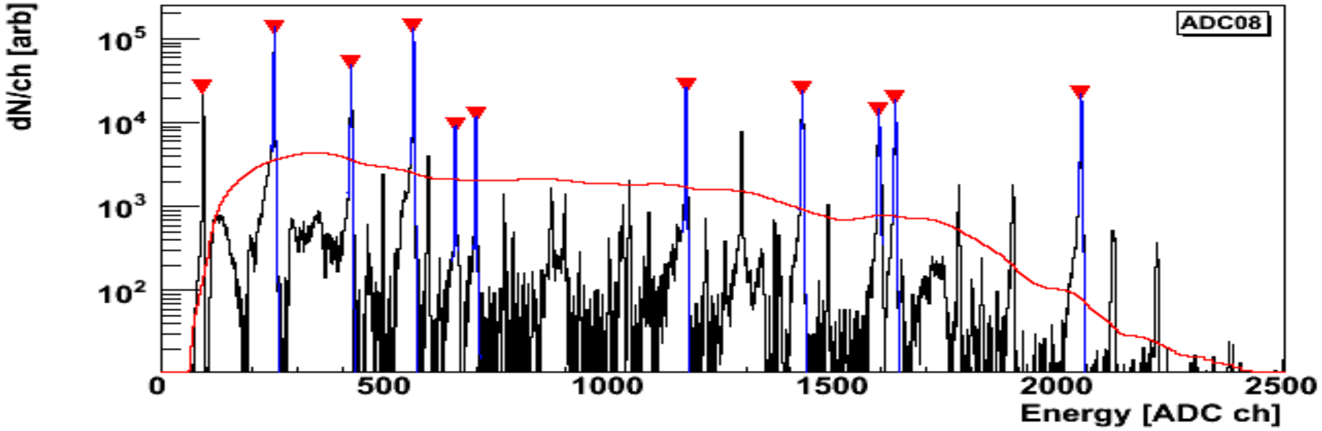
Readout (ADC)

by Sergio Ballestrero

Ge crystal calibration

- ^{152}Eu reference source allows for definition of the parameters describing functional relation between ADC count and E
  - Known γ emission lines
- Find the peaks and fit

$$Q \propto N_\gamma \propto E$$

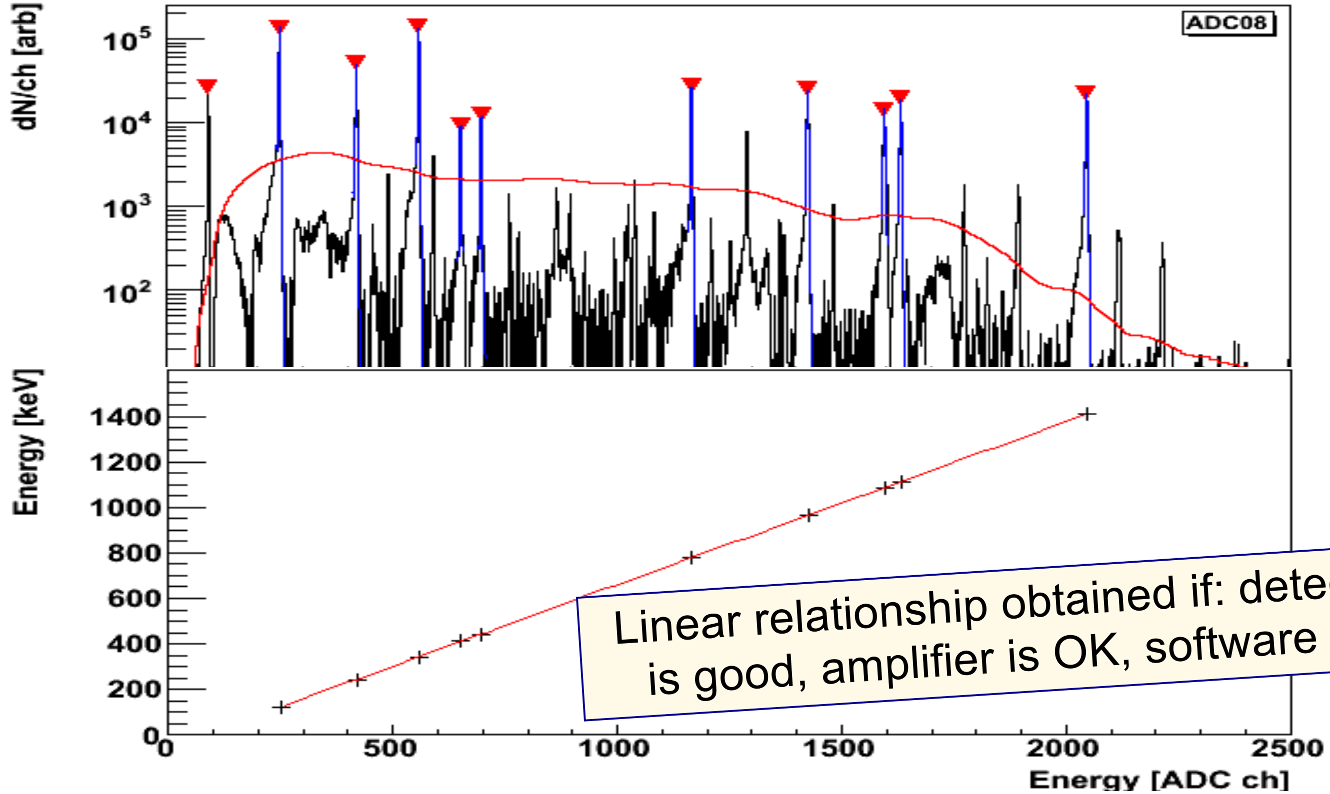


by Sergio Ballestrero

Ge crystal calibration

- ^{152}Eu reference source allows for definition of the parameters describing functional relation between ADC count and E
  - Known γ emission lines
- Find the peaks and fit

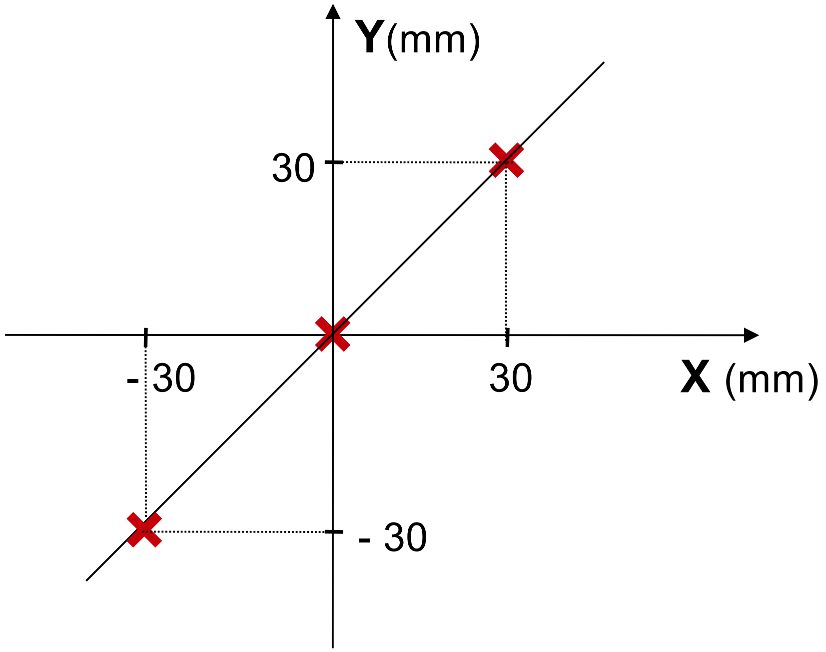
$$Q \propto N_\gamma \propto E$$



Linear relationship obtained if: detector is good, ADC is good, amplifier is OK, software well written, etc.

Back to XDWC: calibration

- XDWC chamber have 3 calibration inputs
  - allow for independent calibrations of X and Y axes with only 3 different sets of data
  - Calibration input simulate signals from particles respectively hitting
    - Right-top (X=Y=30mm)
    - Center (X=Y=0mm)
    - Left-bottom (X=Y=-30mm)
  - Interpolating the three points in t-x space, the parameters of the calibration equation can be measured

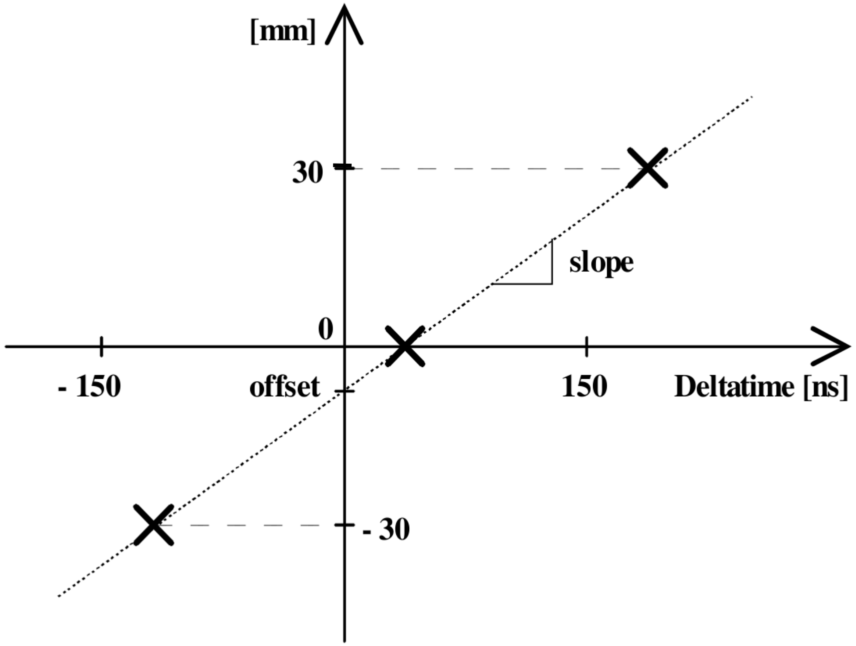


$$x = \alpha t^* + \beta$$

- Calibration shall be done with final setup and TDC

Back to XDWC: calibration

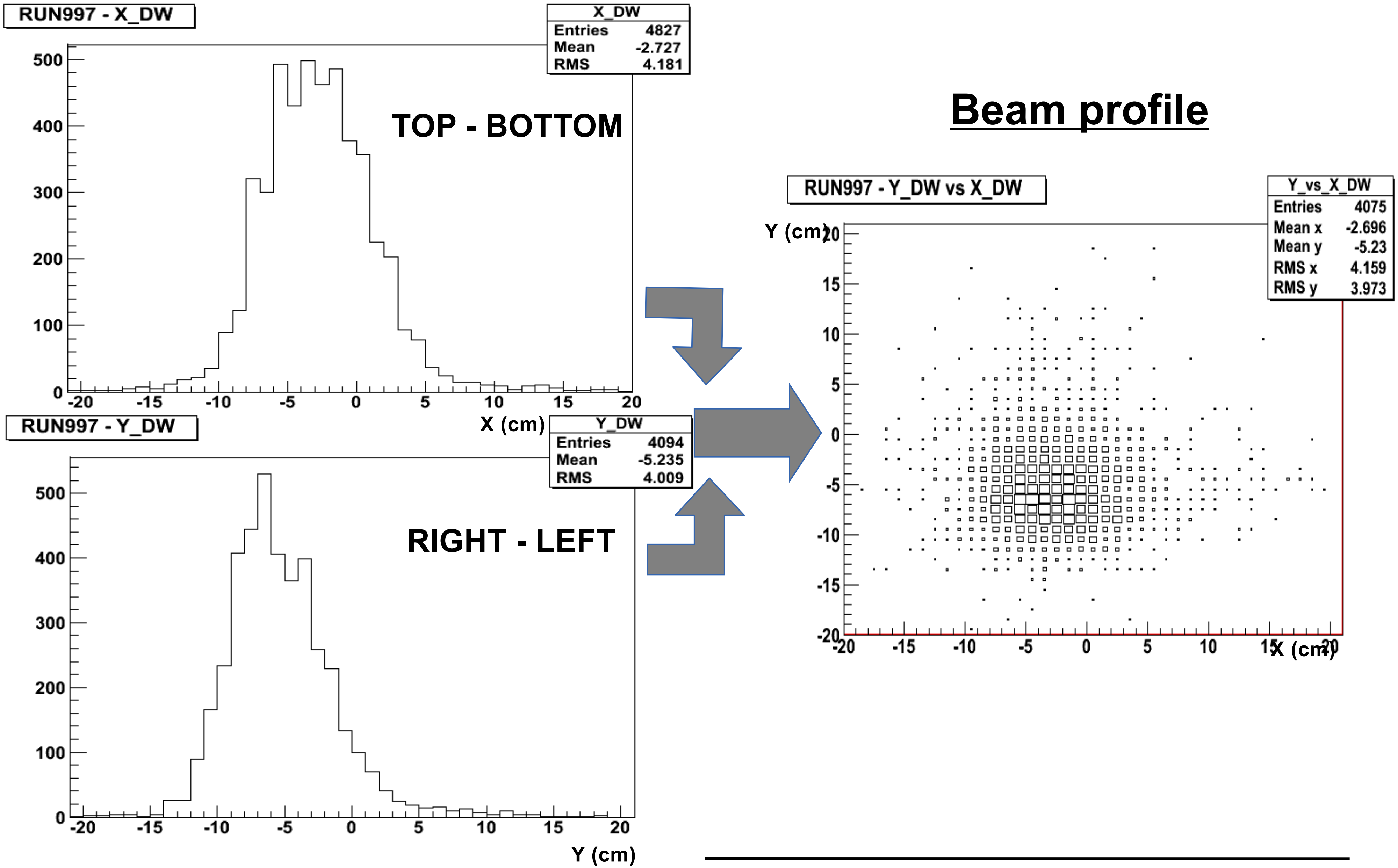
- XDWC chamber have 3 calibration inputs
  - allow for independent calibrations of X and Y axes with only 3 different sets of data
  - Calibration input simulate signals from particles respectively hitting
    - Right-top (X=Y=30mm)
    - Center (X=Y=0mm)
    - Left-bottom (X=Y=-30mm)
  - Interpolating the three points in t-x space, the parameters of the calibration equation can be measured



$$x = \alpha t^* + \beta$$

- Calibration shall be done with final setup and TDC

Calibrated XDWC



Beam profile

Wrap-up

- Digitization techniques produce data directly manageable by digital systems (e.g. a computer)
  - Greatly simplifies the down-stream data-handling
  - Available on a variety of platforms: VME, ATCA, PCI, USB, …
  - Root of every modern DAQ system
- Frequently you have to open the "black box" and see where numbers come from
  - Real electronics does not behave as the ideal one

- Trade-offs between speed/precision/cost exist
  - You have to choose the solution that best suits you
- Physics quantities are derived from raw data via calibration
  - Calibration procedures to be foreseen for your detector/DAQ

Thank you!